

Data collection strategy

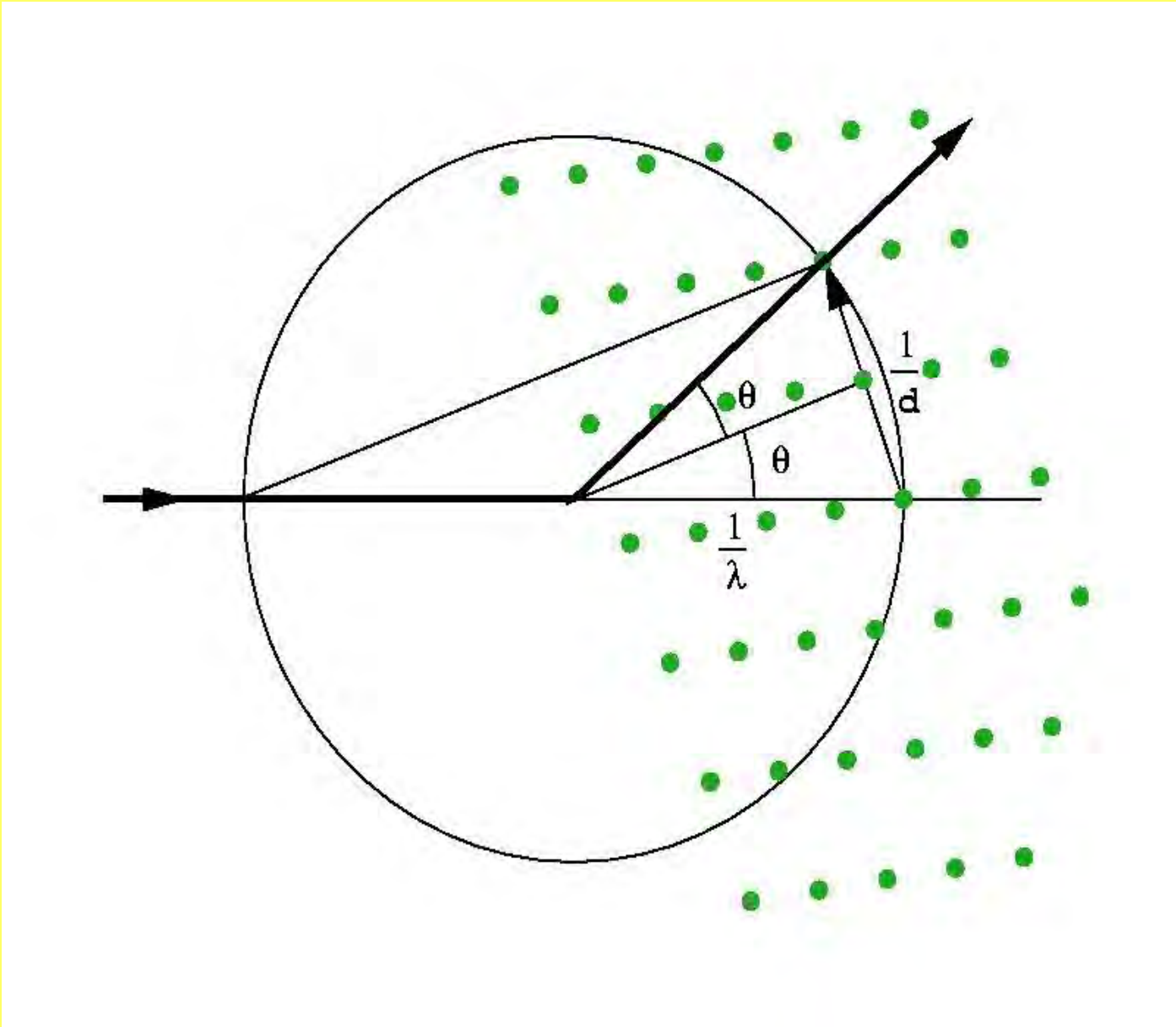
Completeness

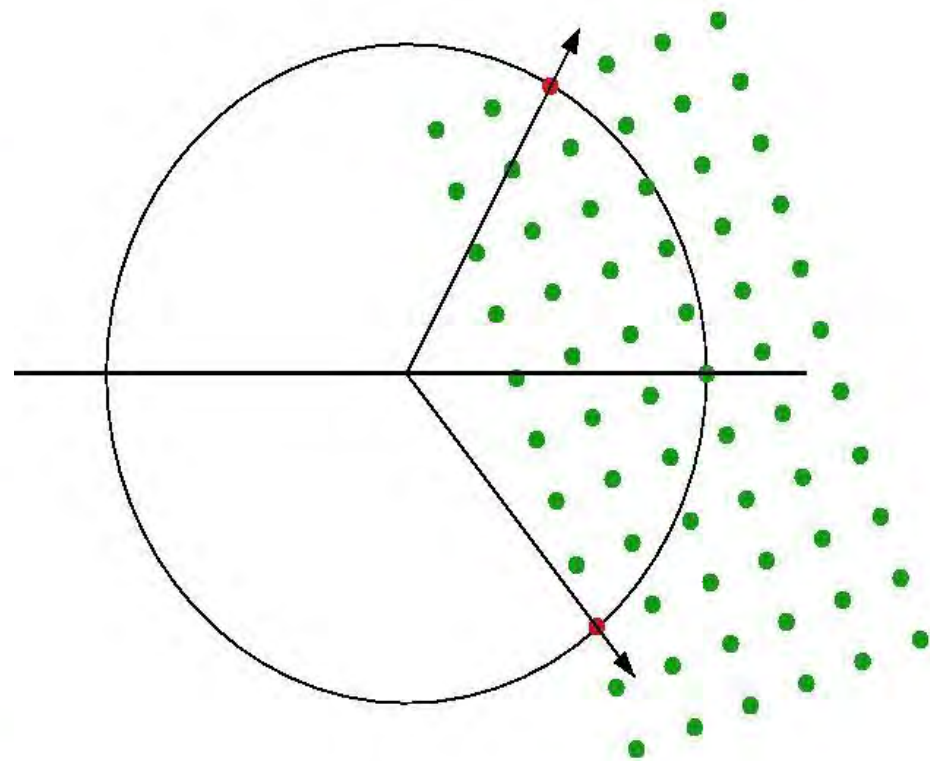
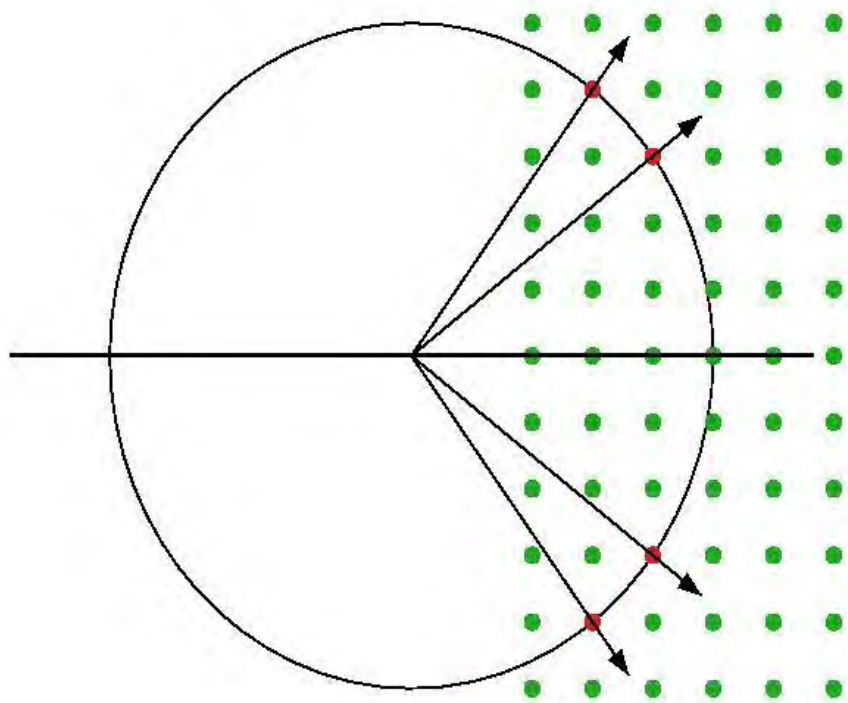
Quantitative
(indices)

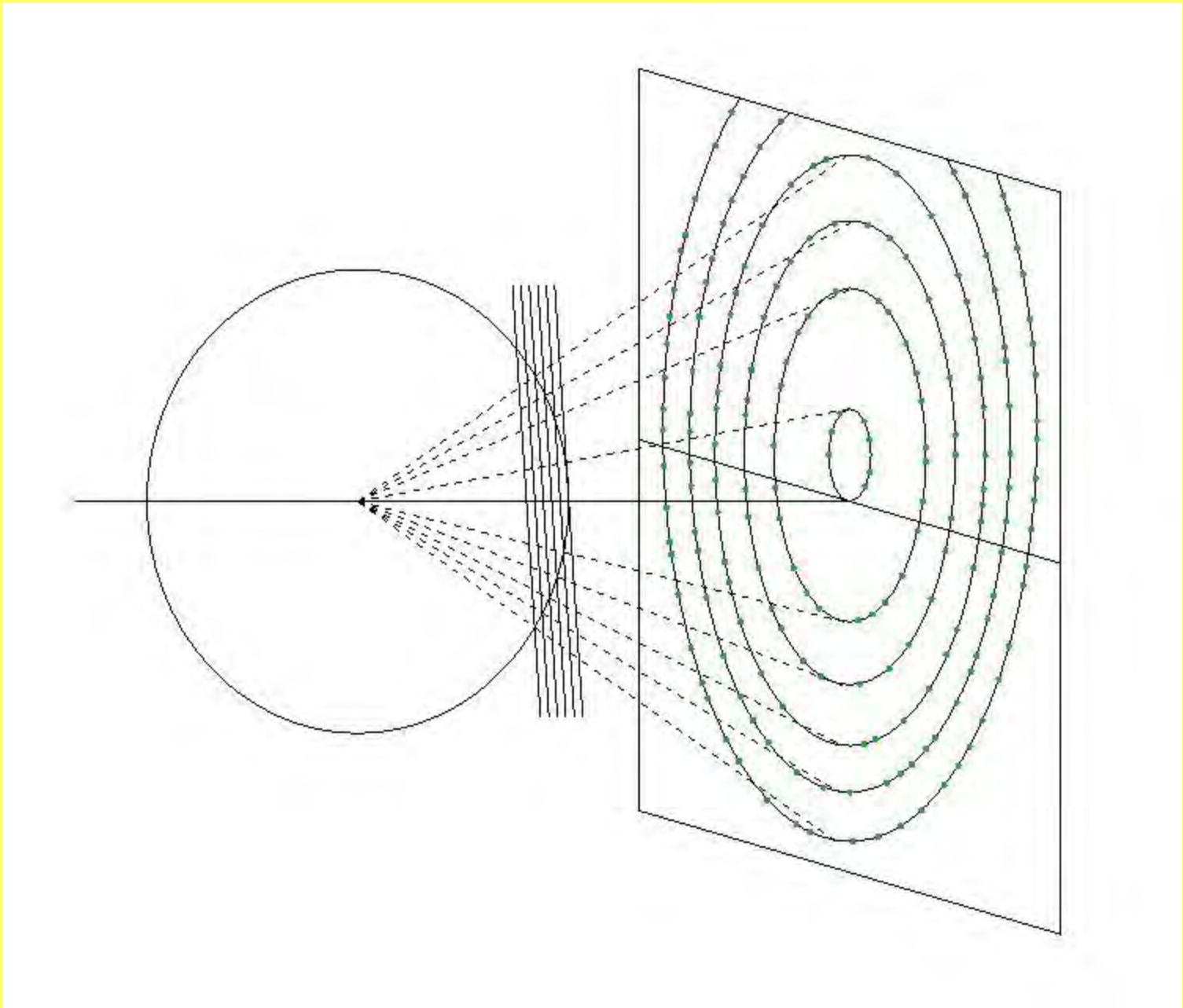
- asymmetric unit
- mosaicity
- overlap of profiles
- blind region
- rotation range
- non-equiv. indexing

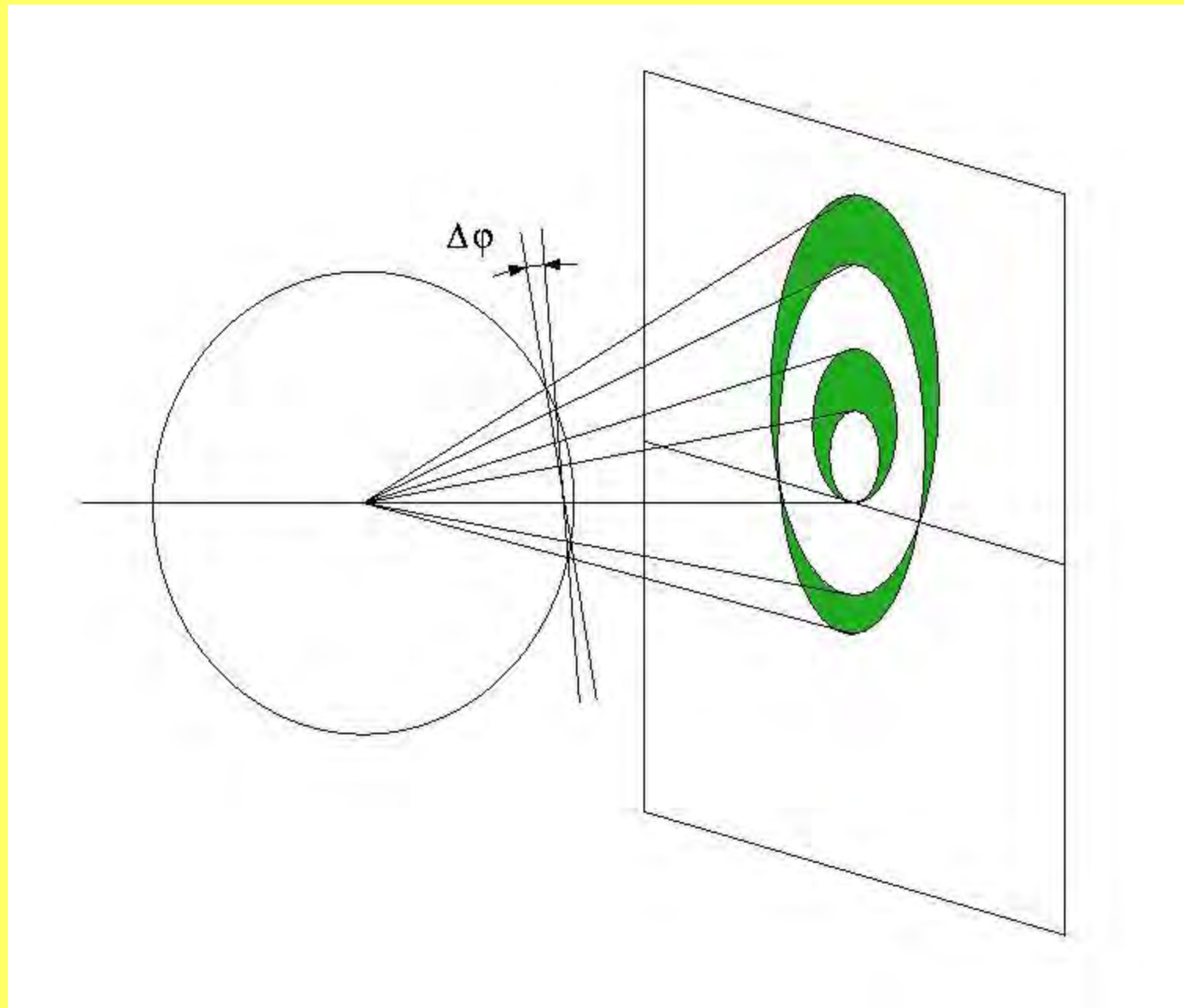
Qualitative
(intensities)

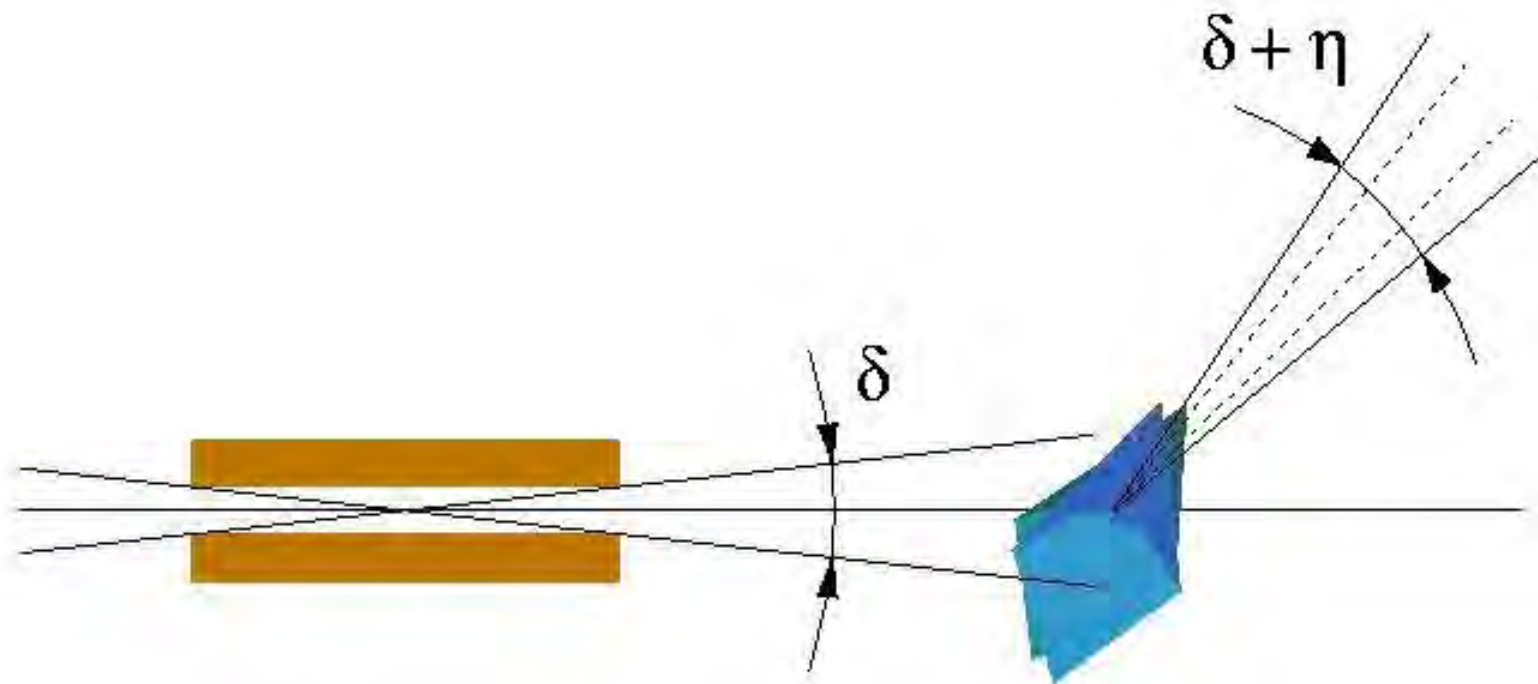
- overloads
- multiplicity
- Rmerge, I/sigma
- sigma estimation

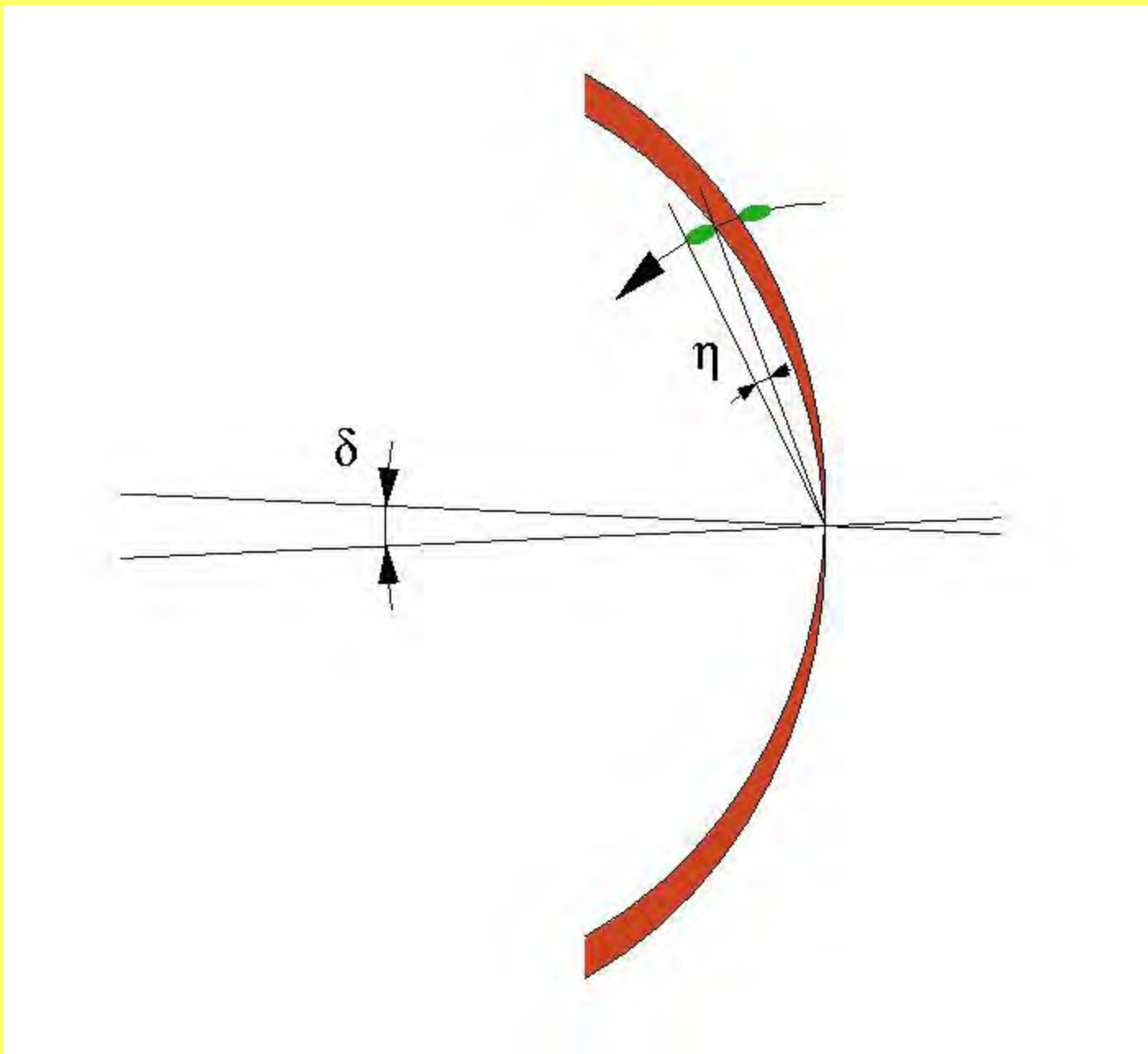


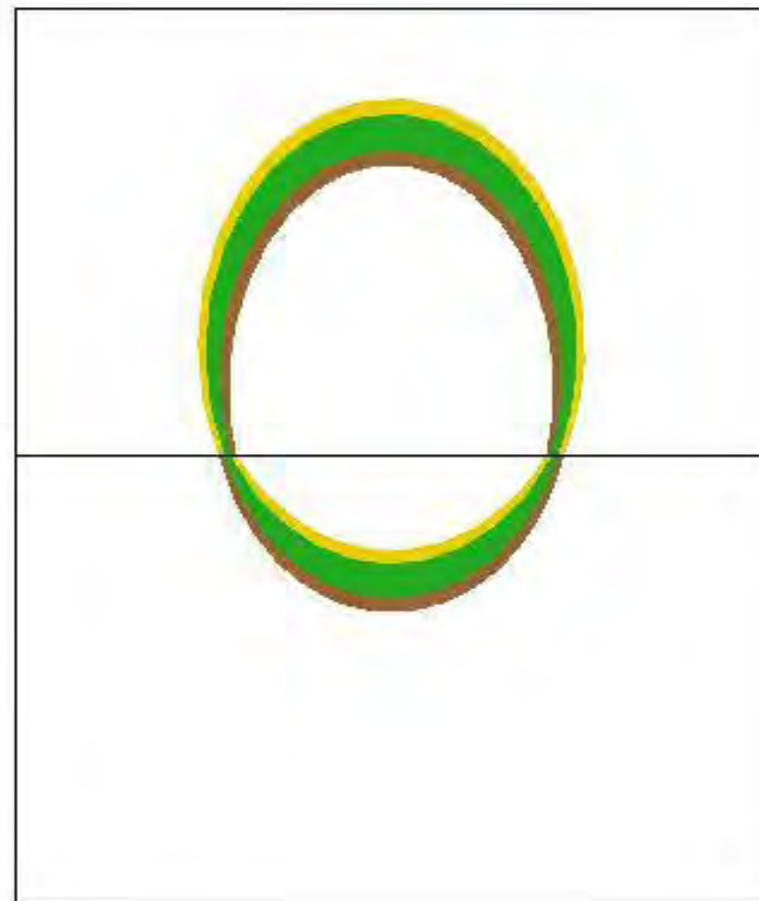
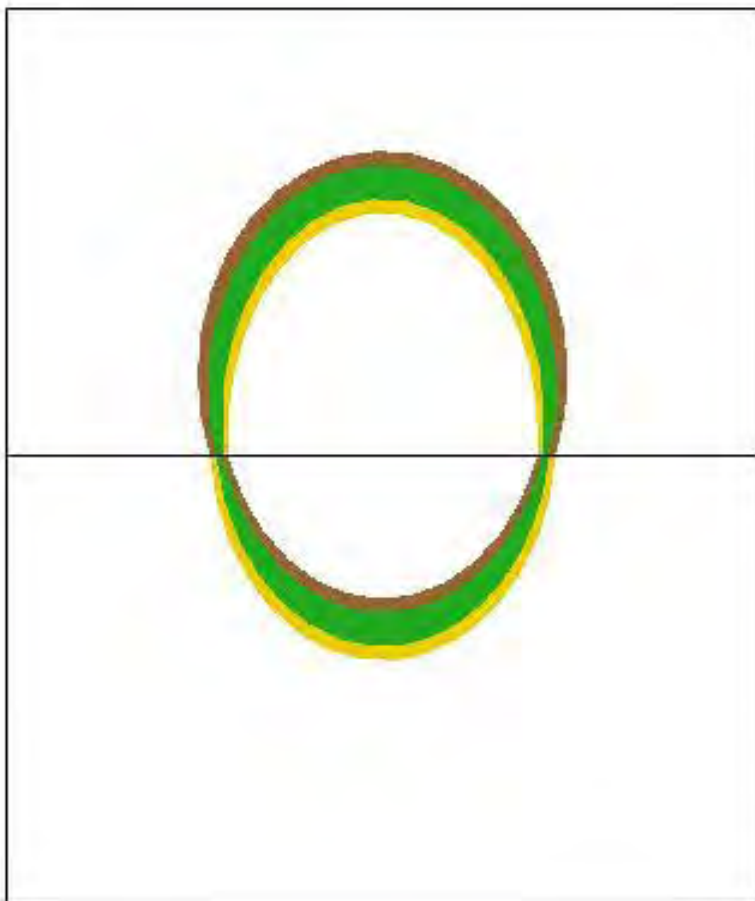


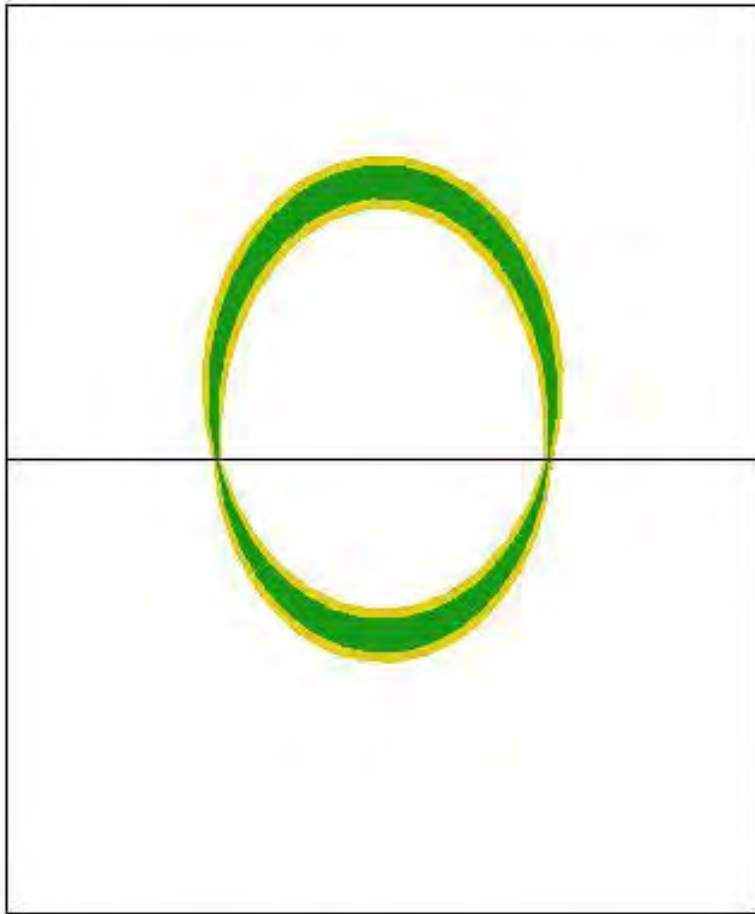




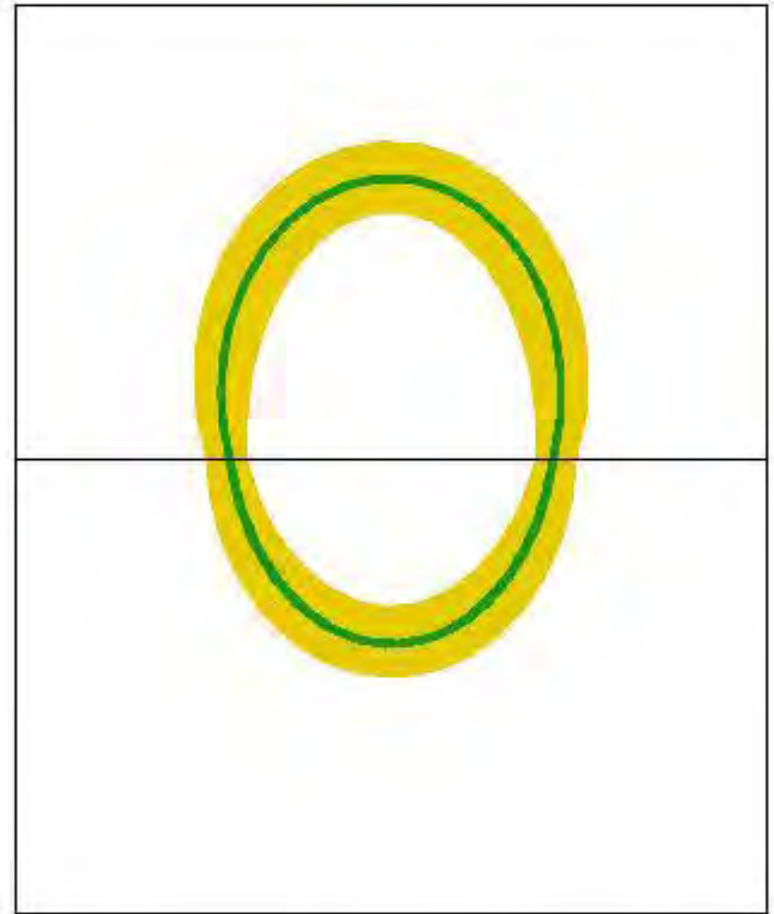




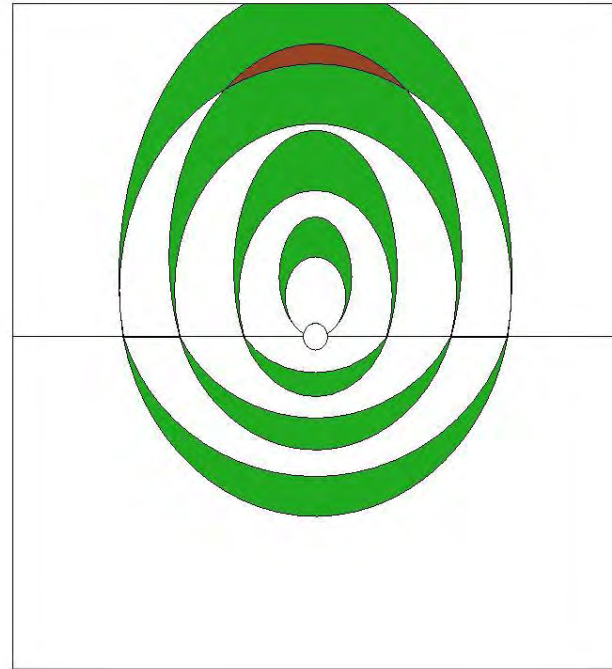
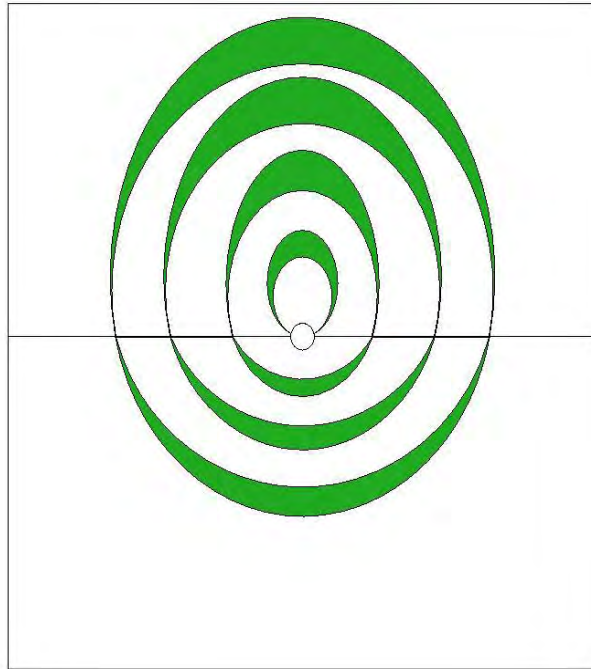
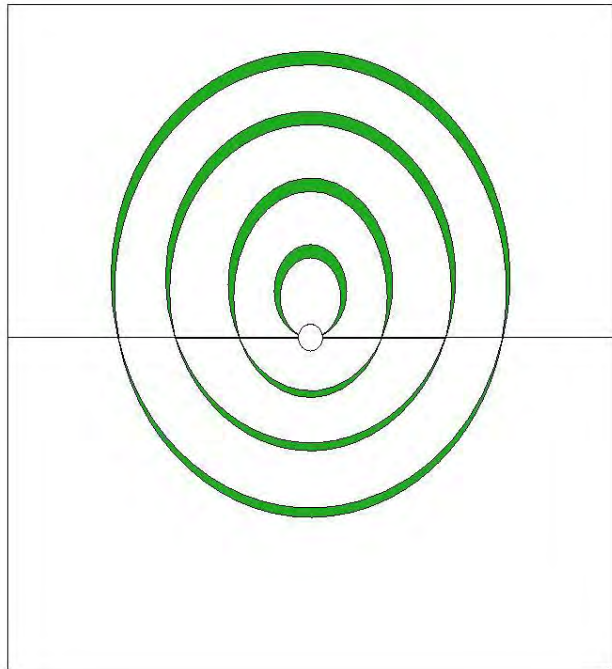


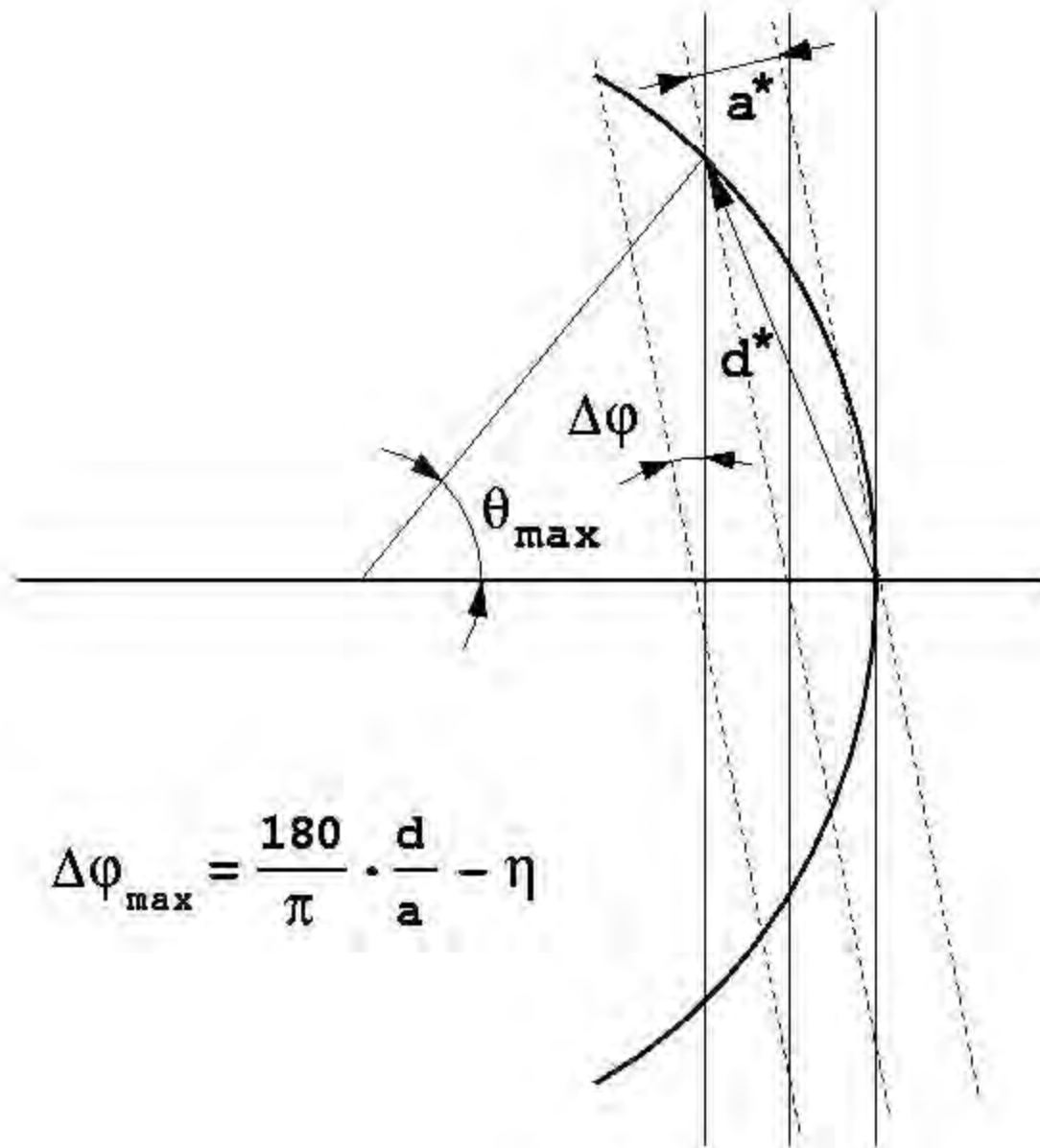


$$\eta < \Delta\phi$$



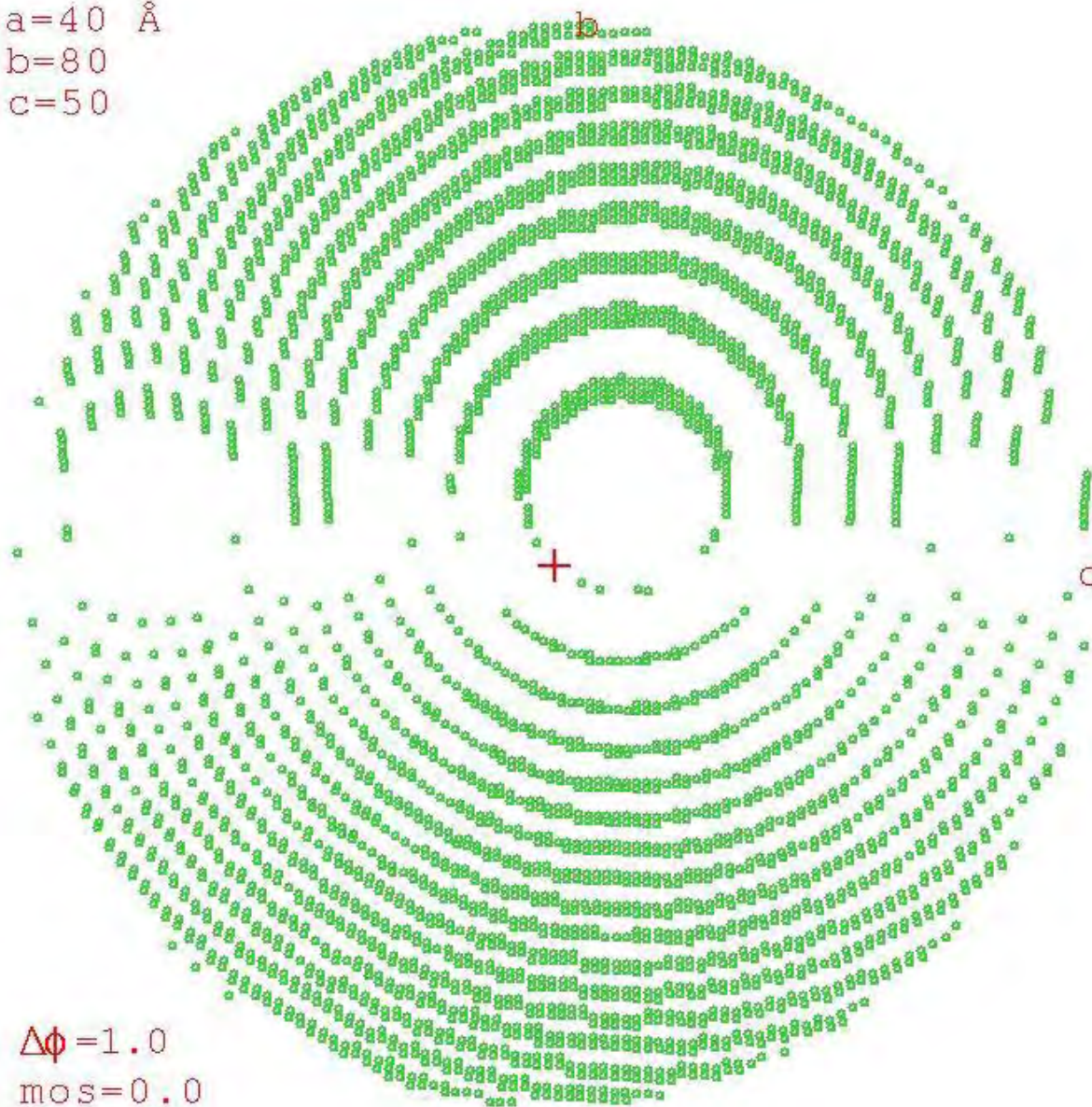
$$\eta \sim \Delta\phi$$



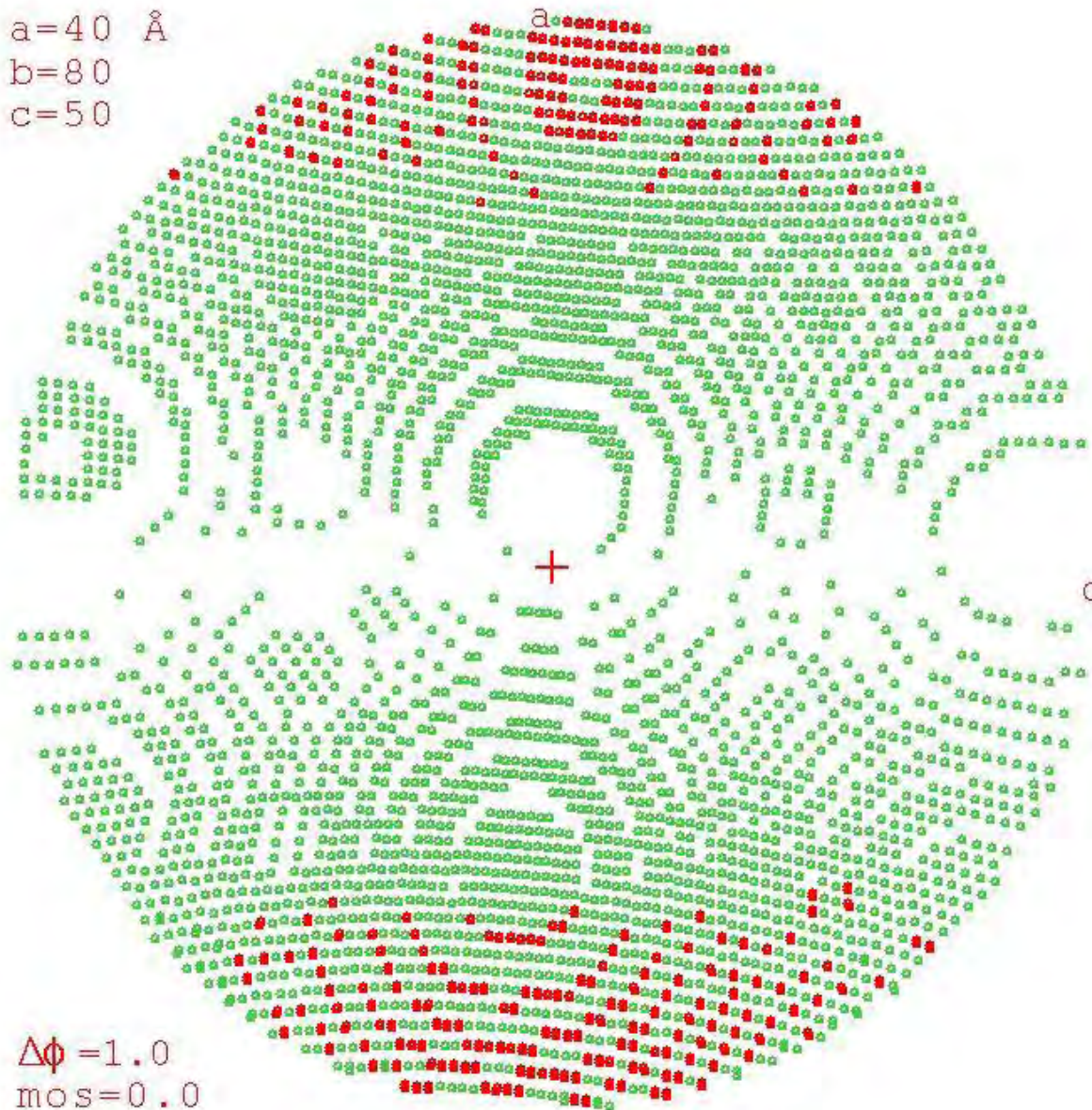


$$\Delta\phi_{\max} = \frac{180}{\pi} \cdot \frac{d}{a} - \eta$$

a=40 Å
b=80
c=50

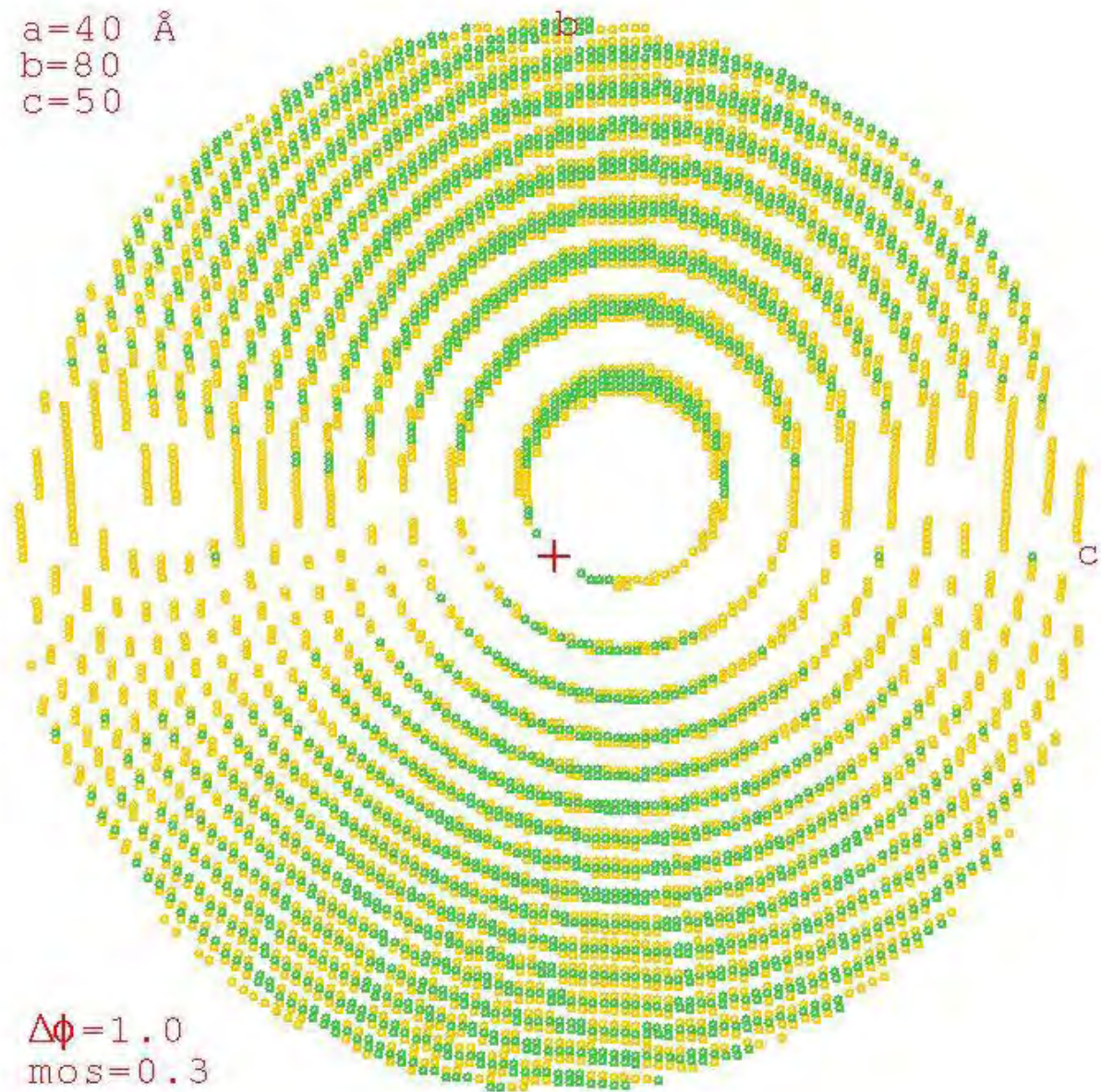


a=40 Å
b=80
c=50



$\Delta\phi = 1.0$
mos = 0.0

$a=40 \text{ \AA}$
 $b=80$
 $c=50$



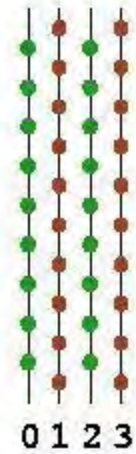
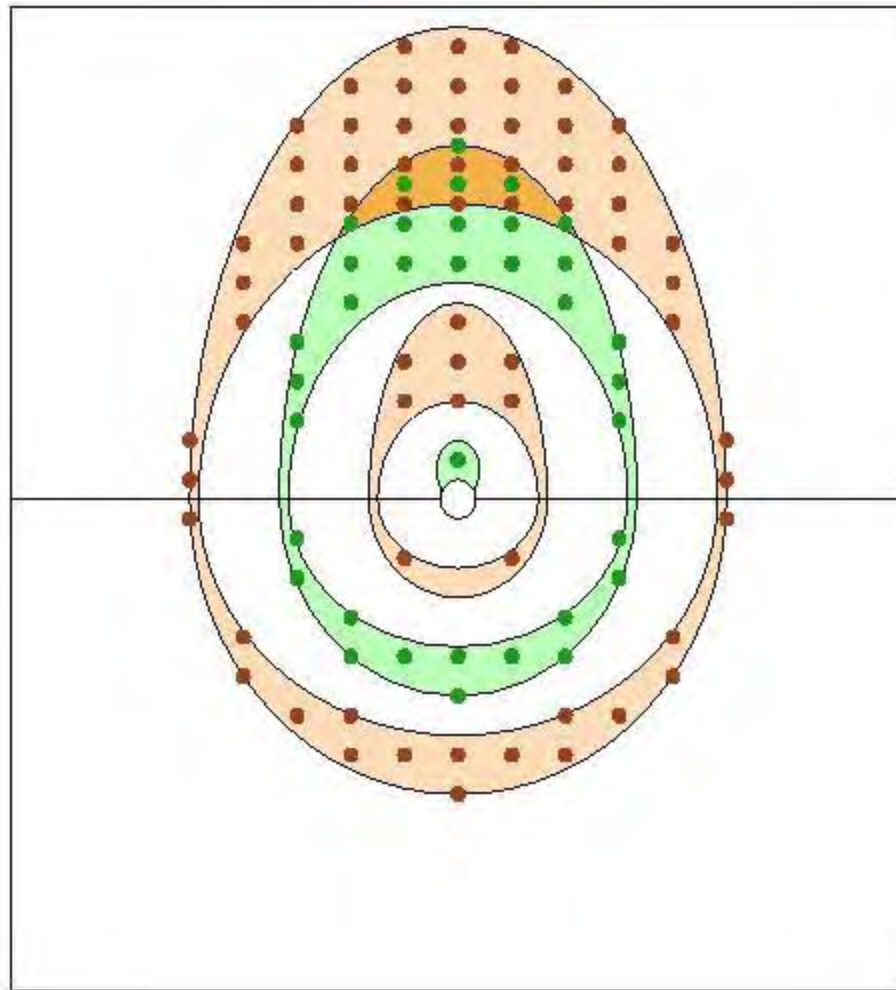
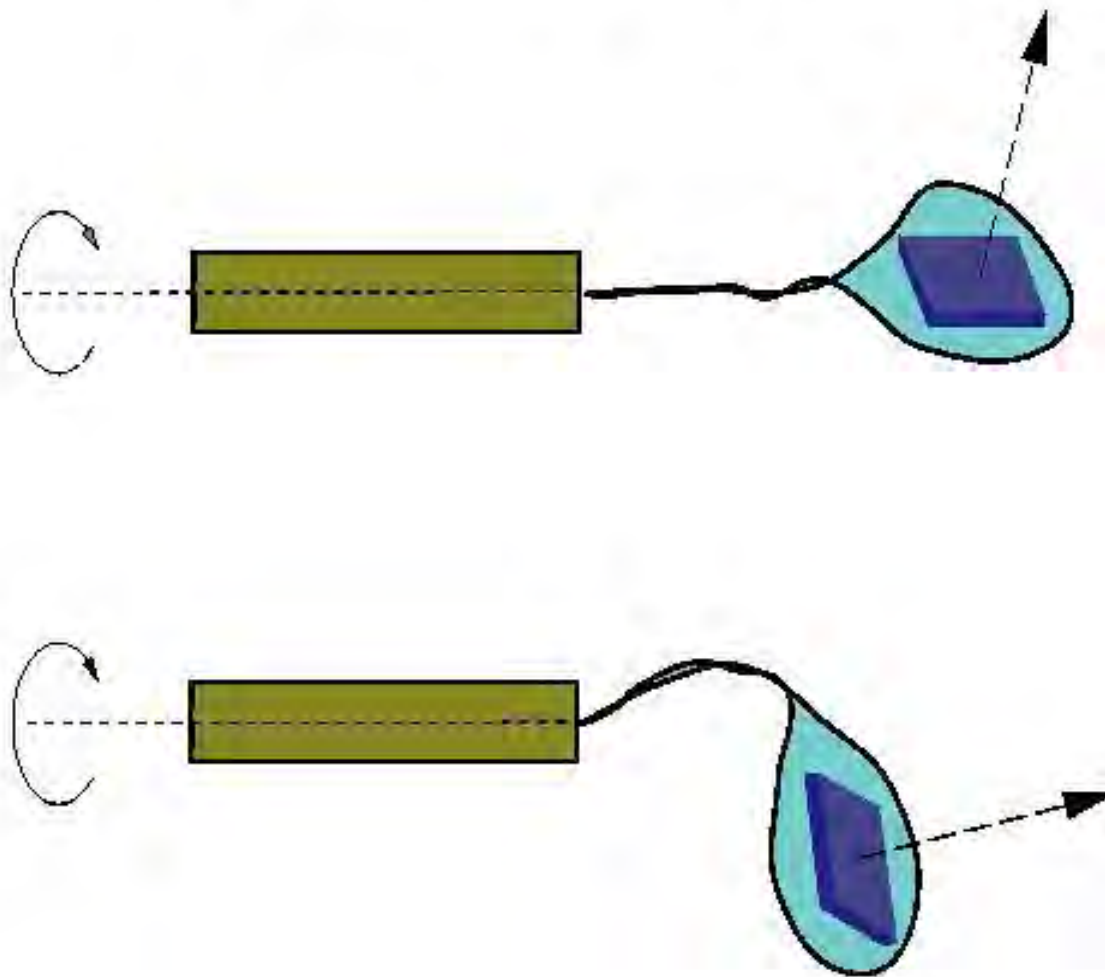
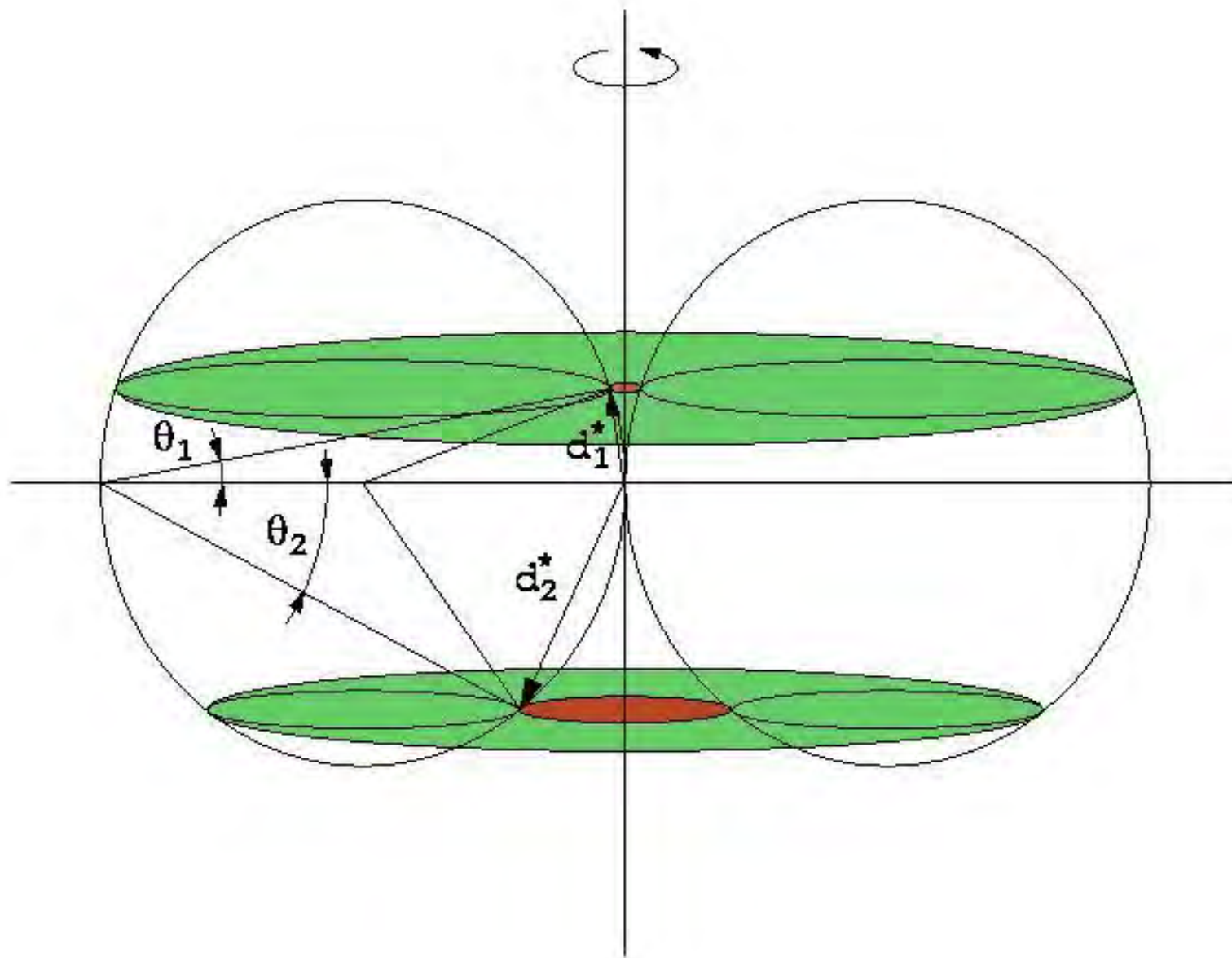
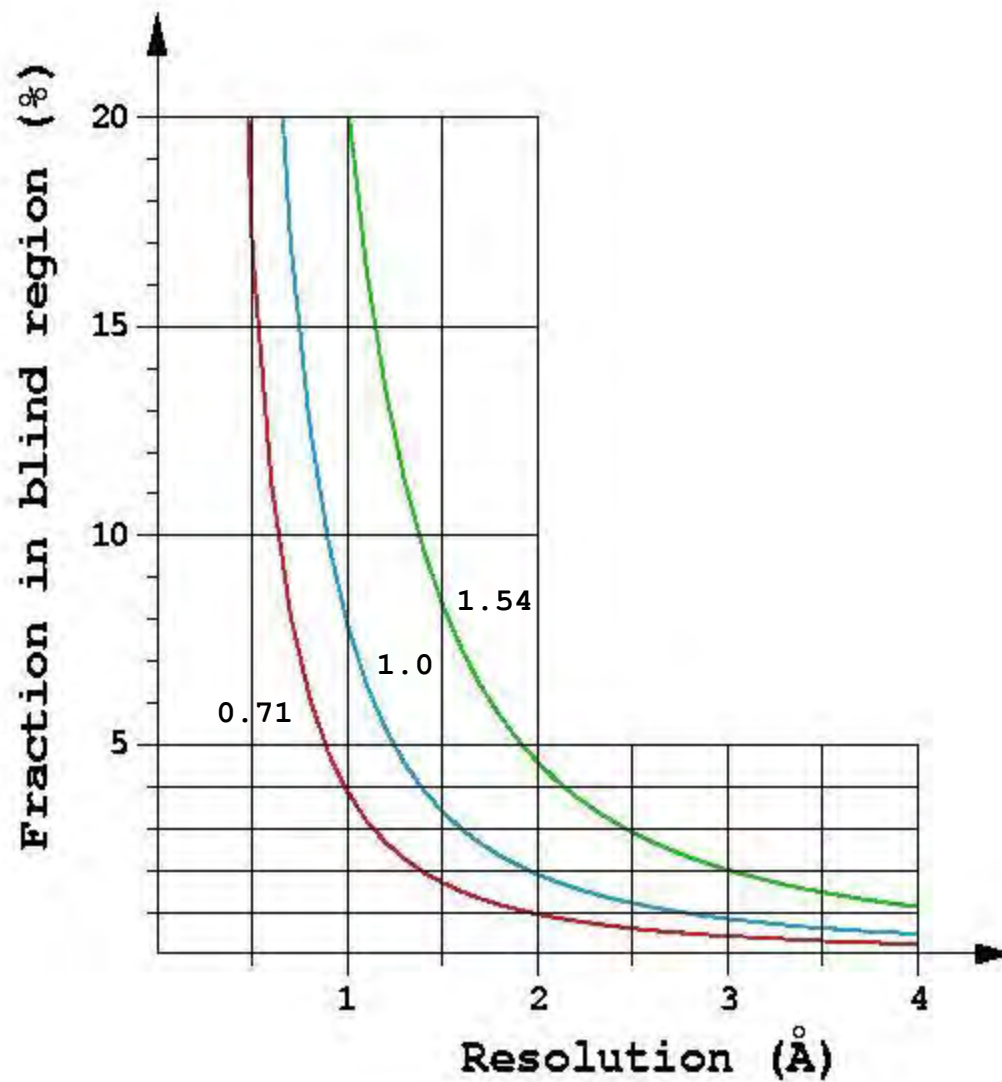
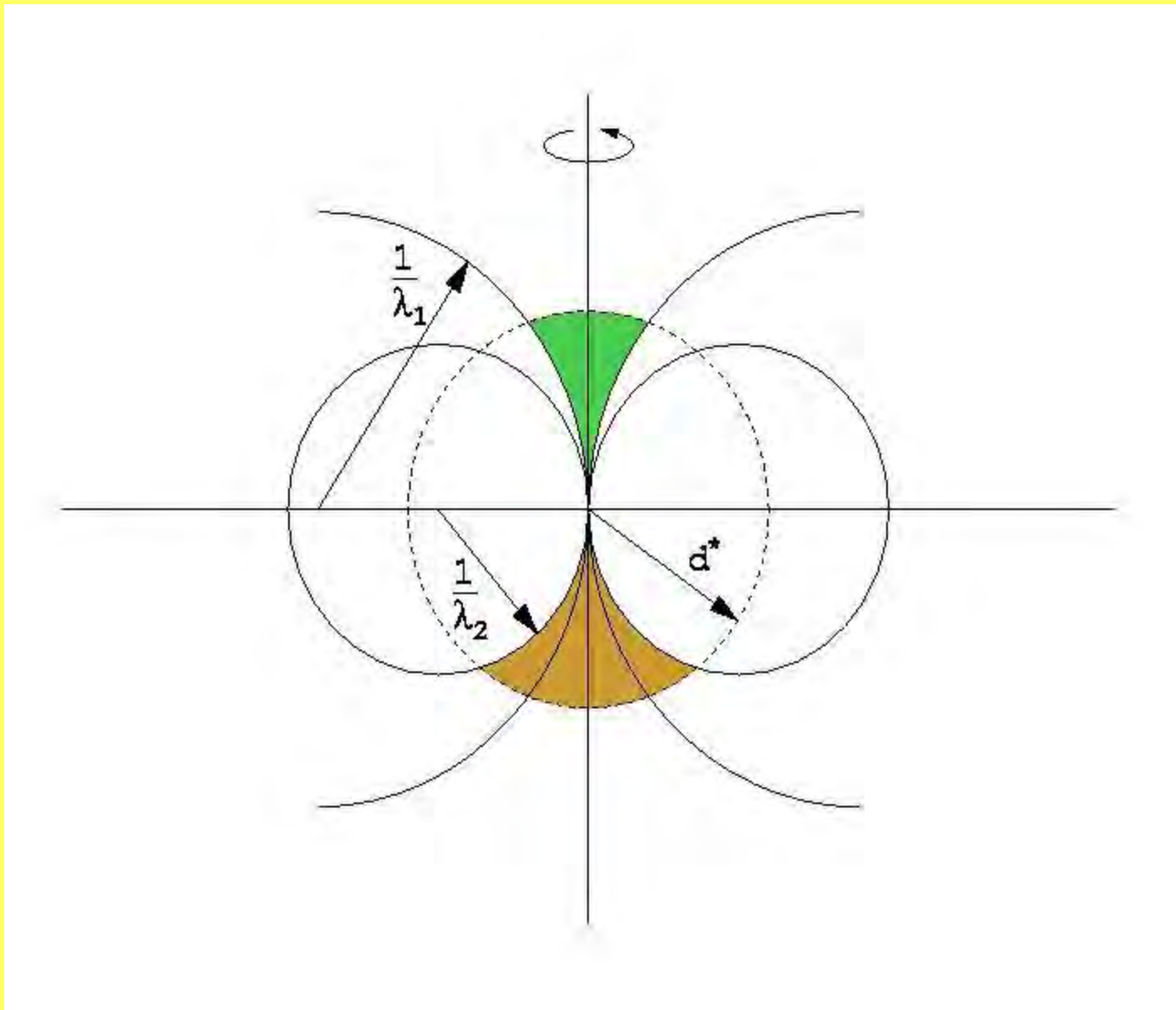


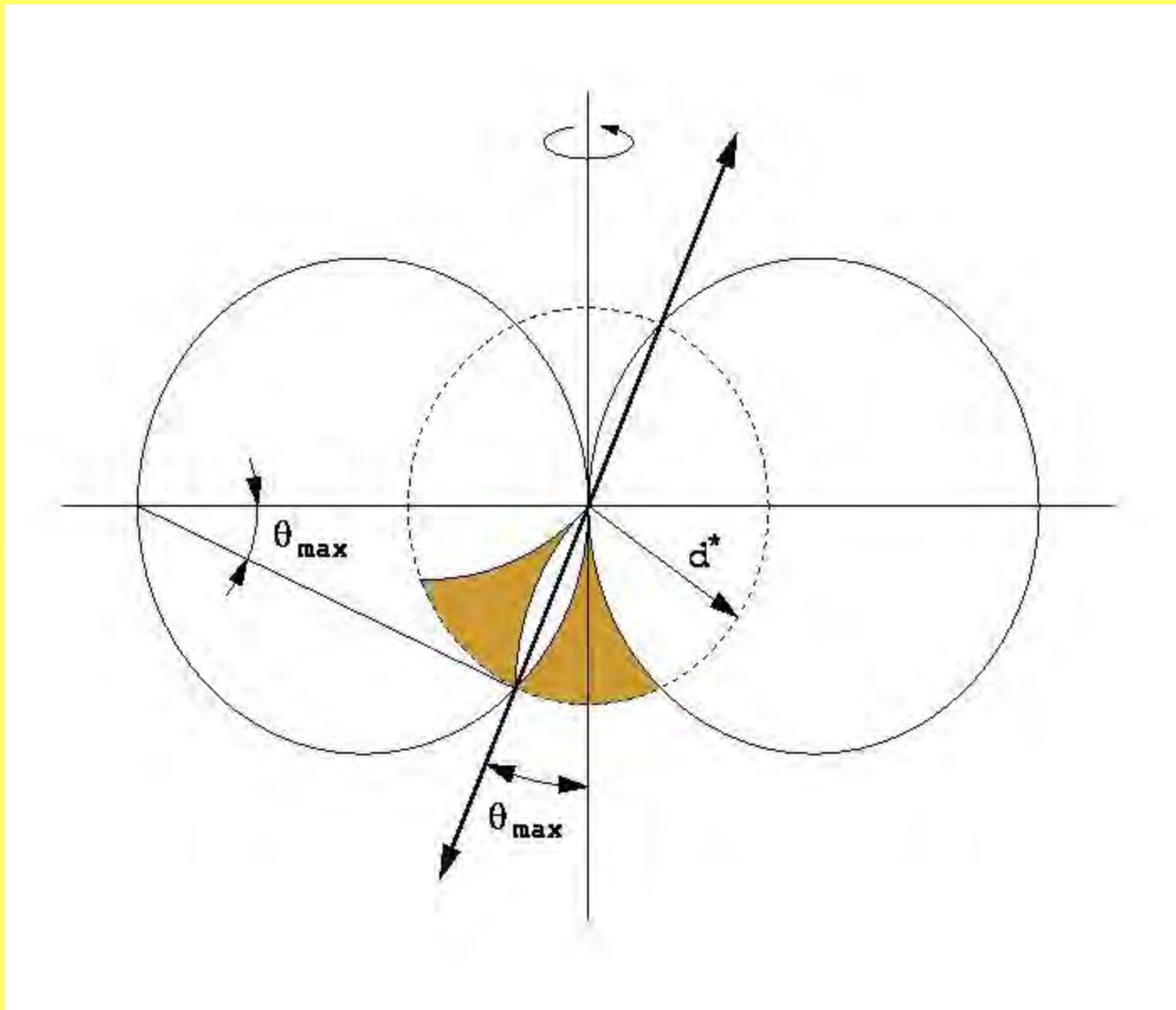
Plate crystal with long axis

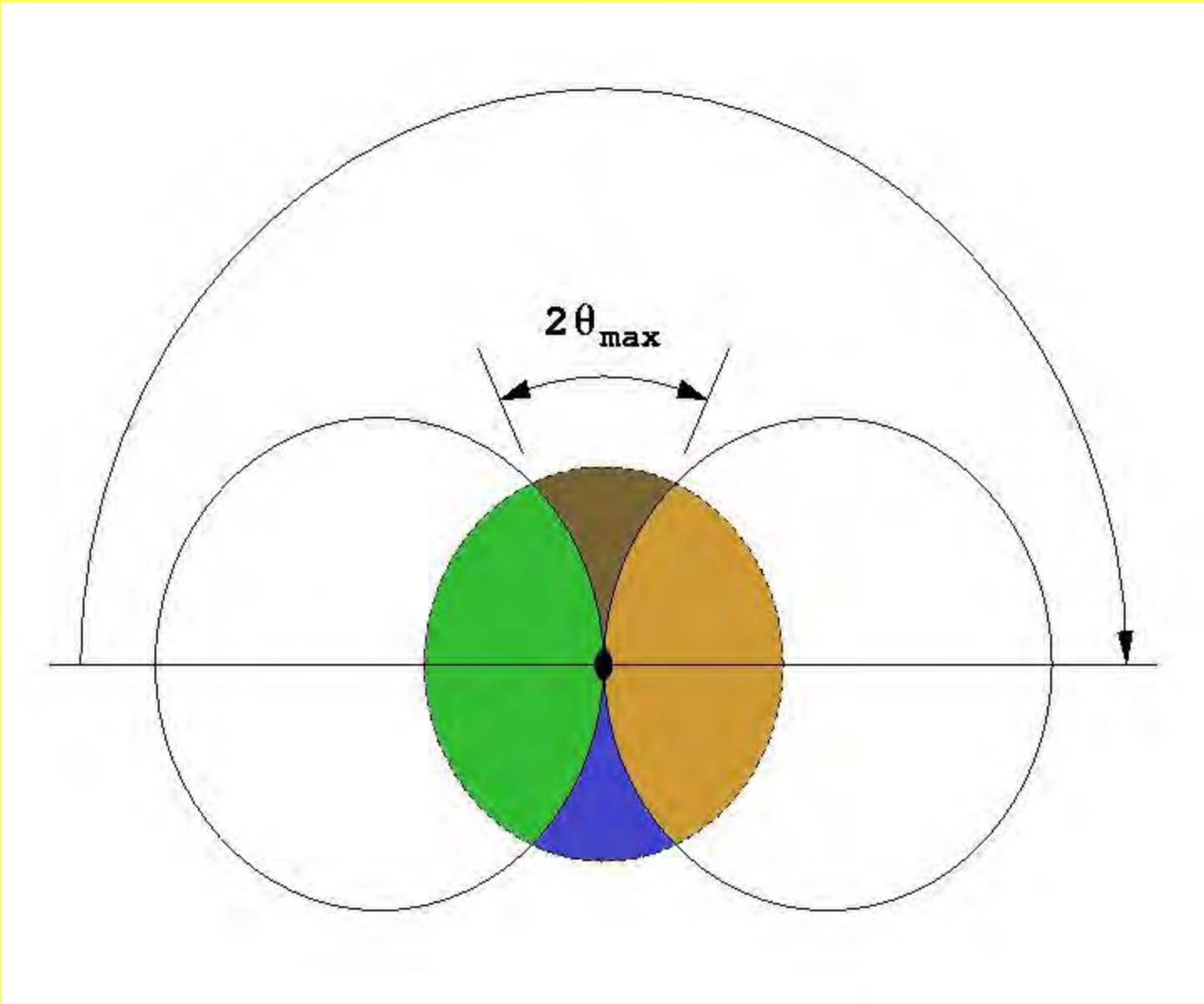


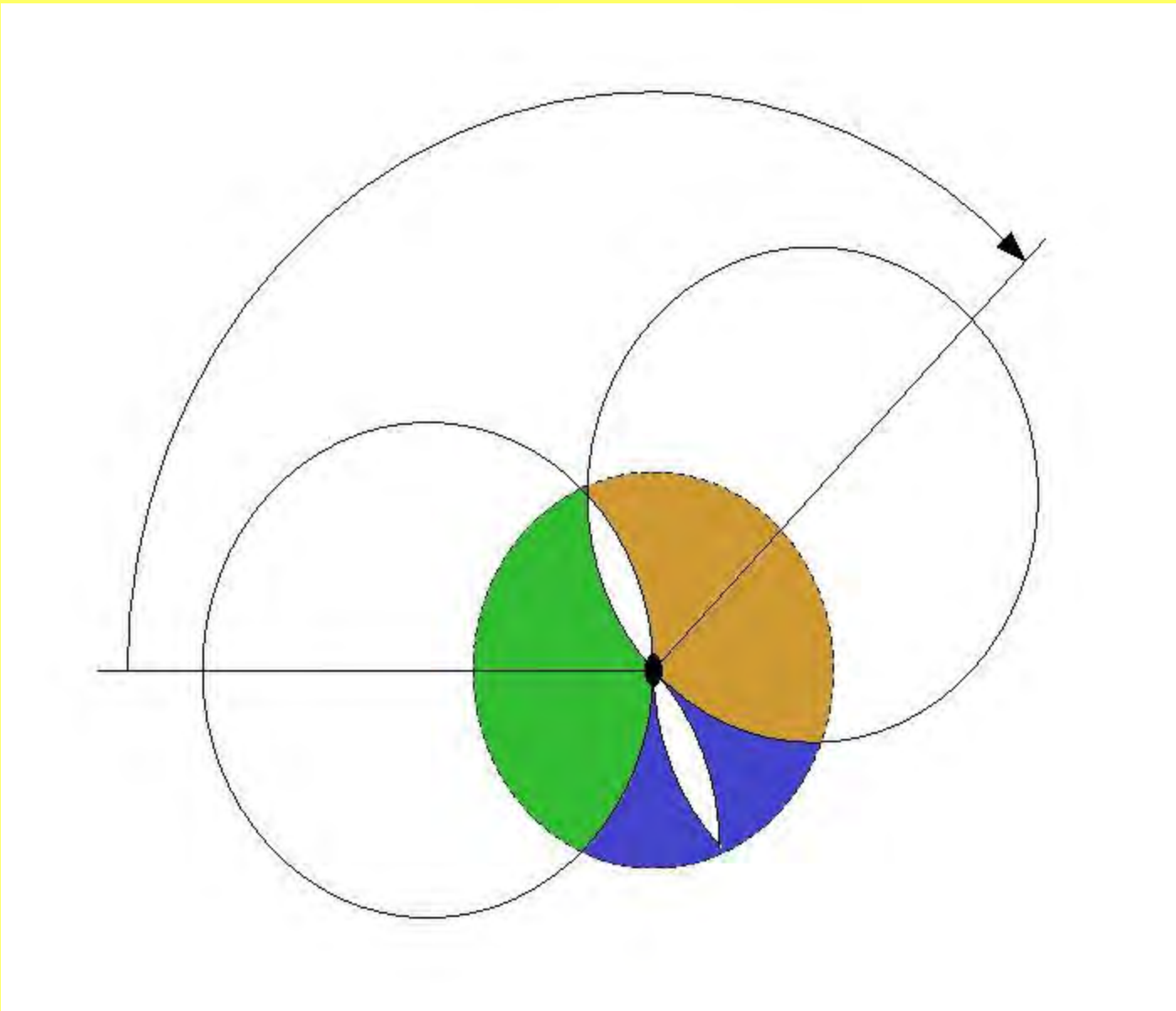


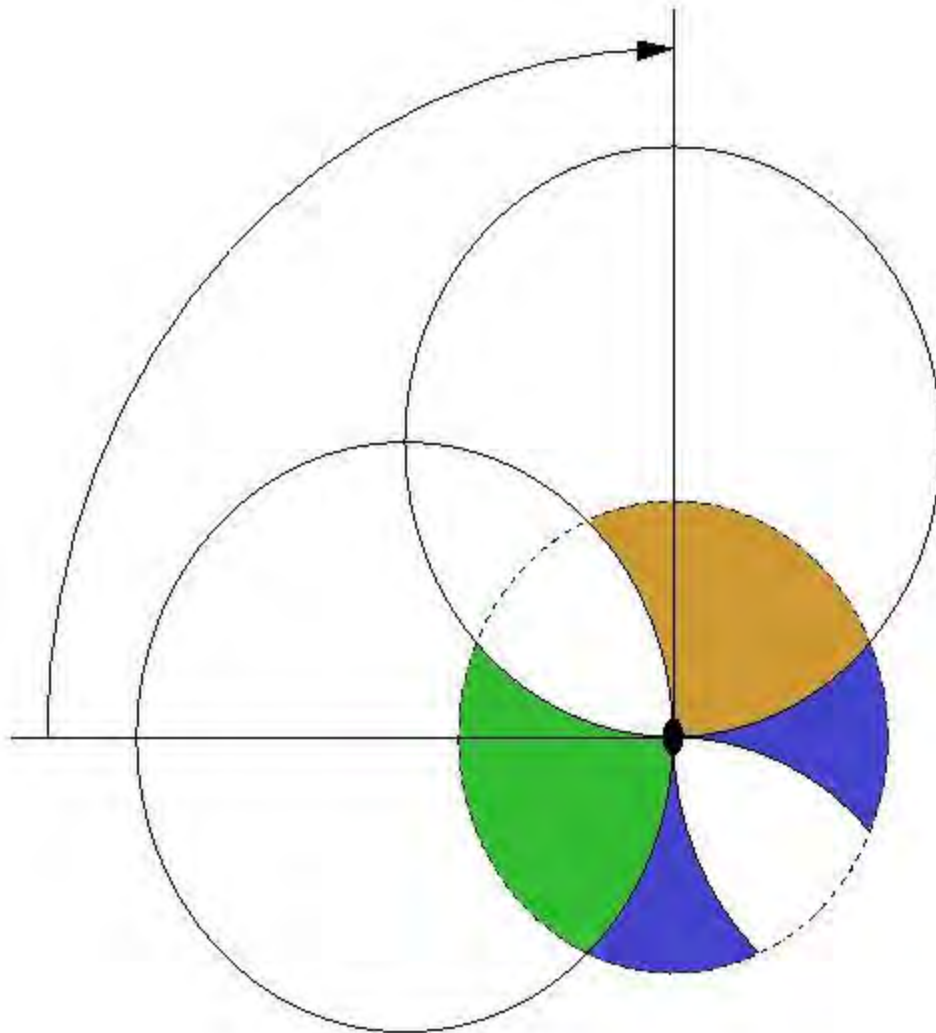


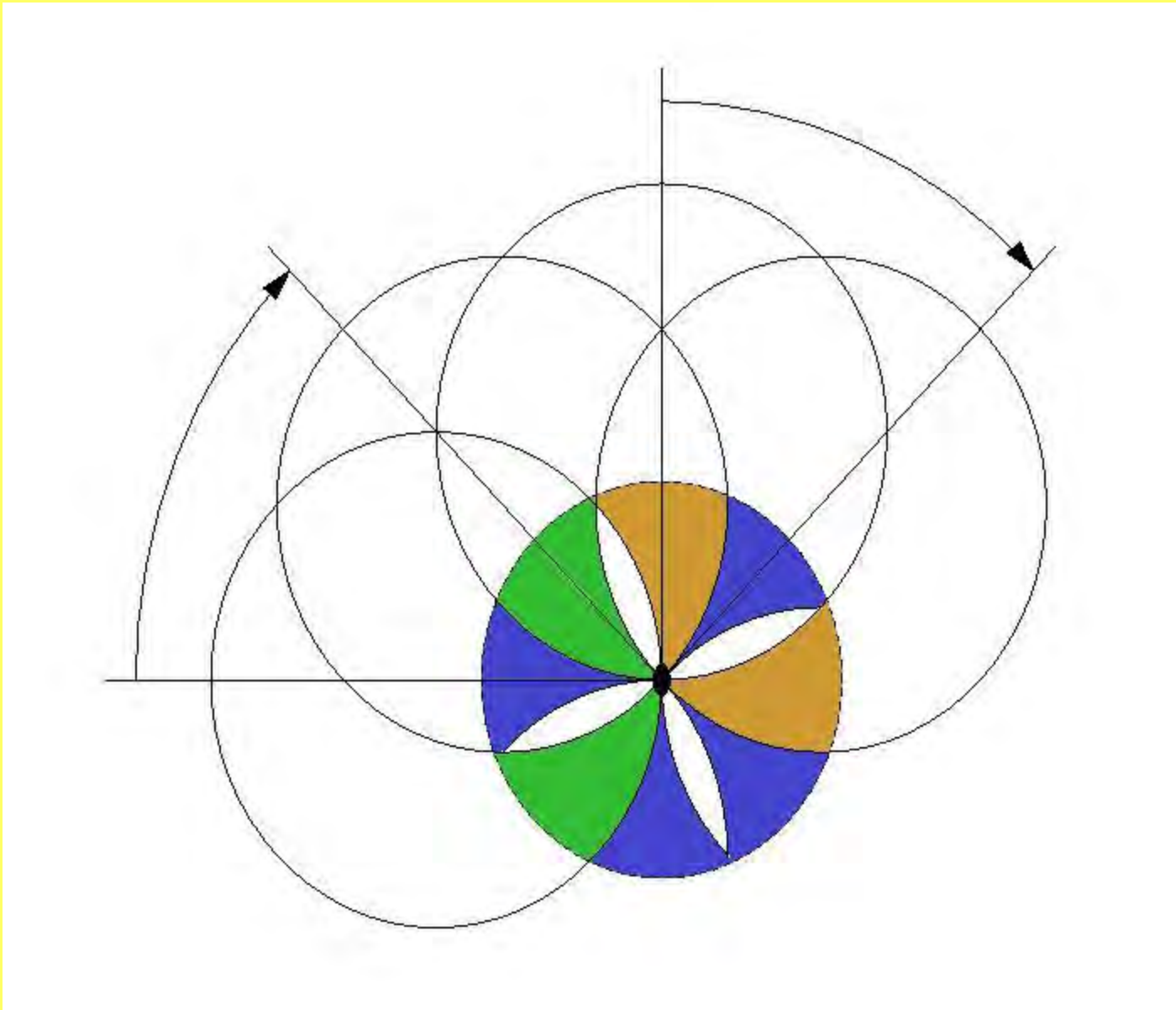


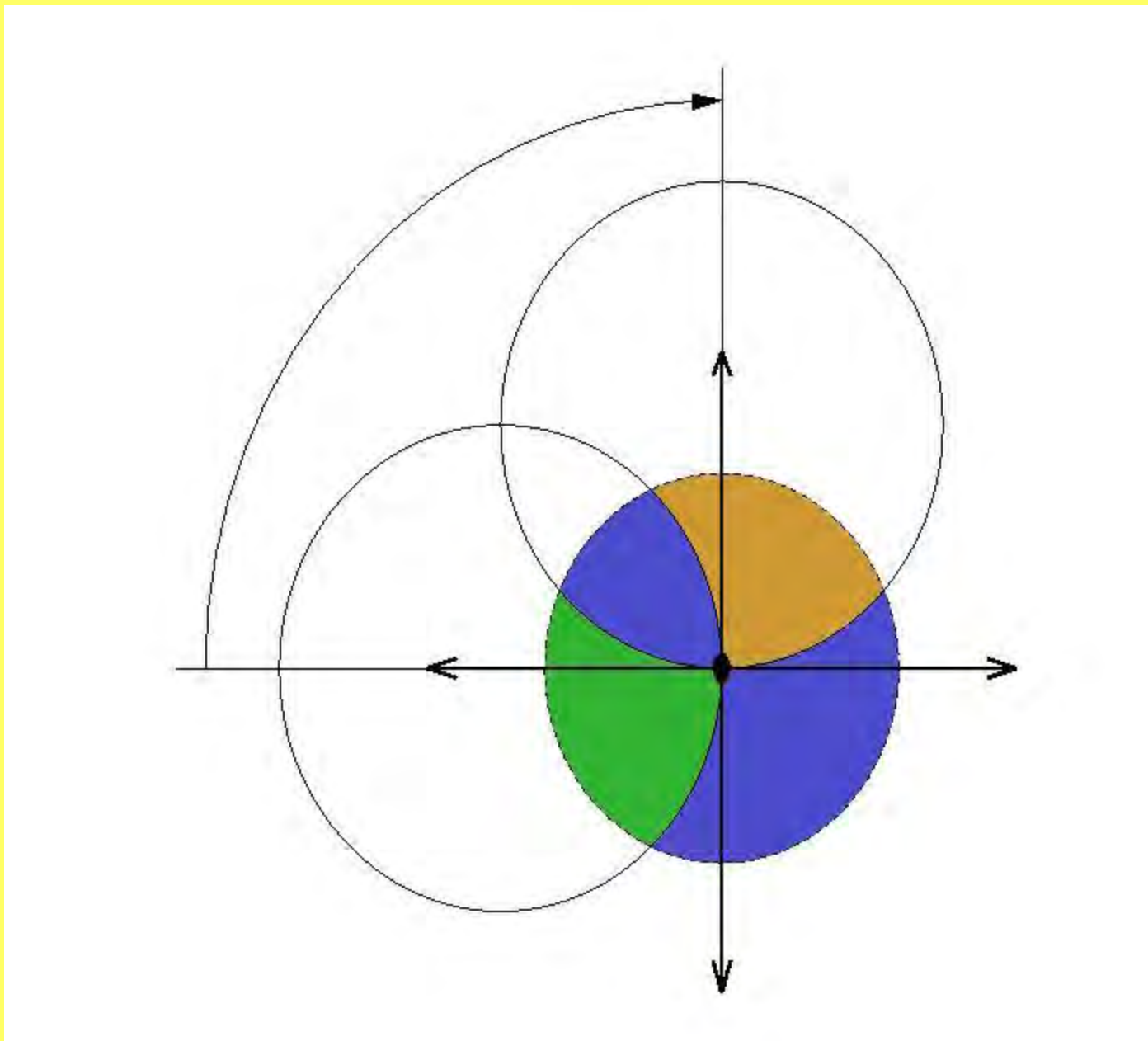


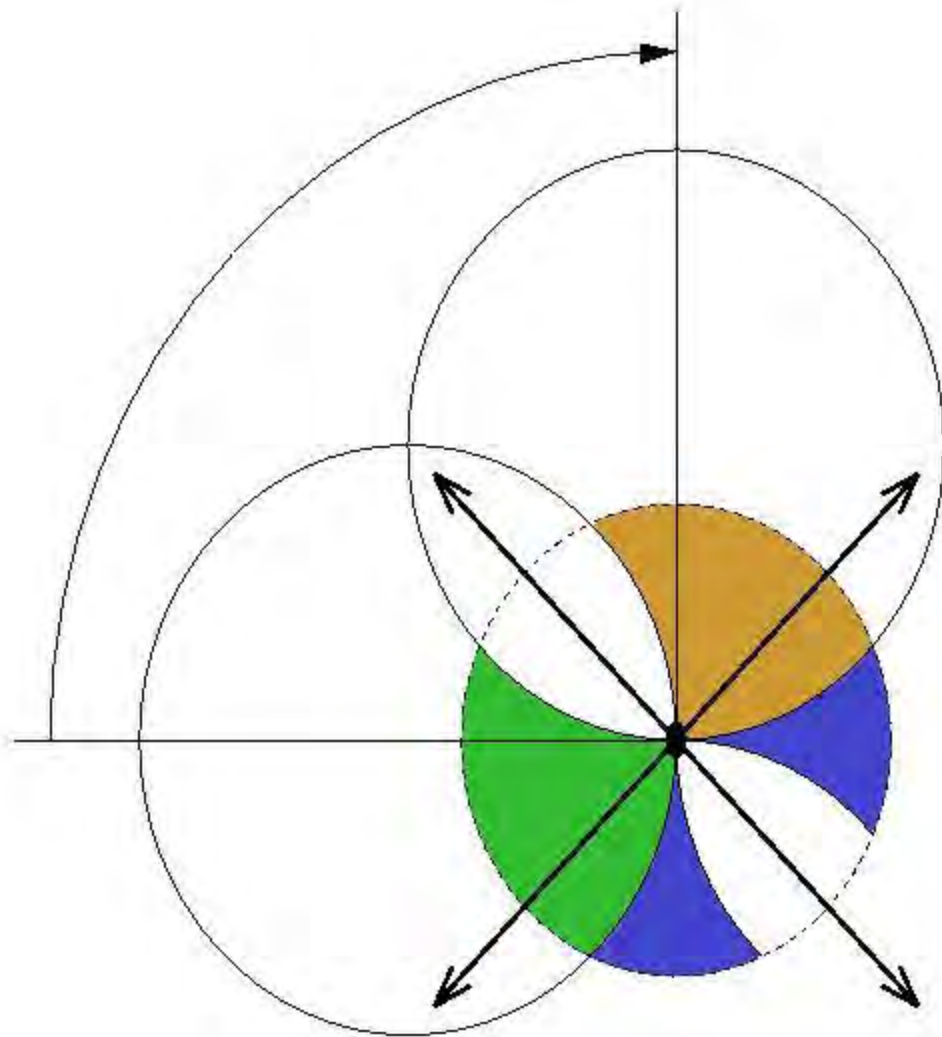




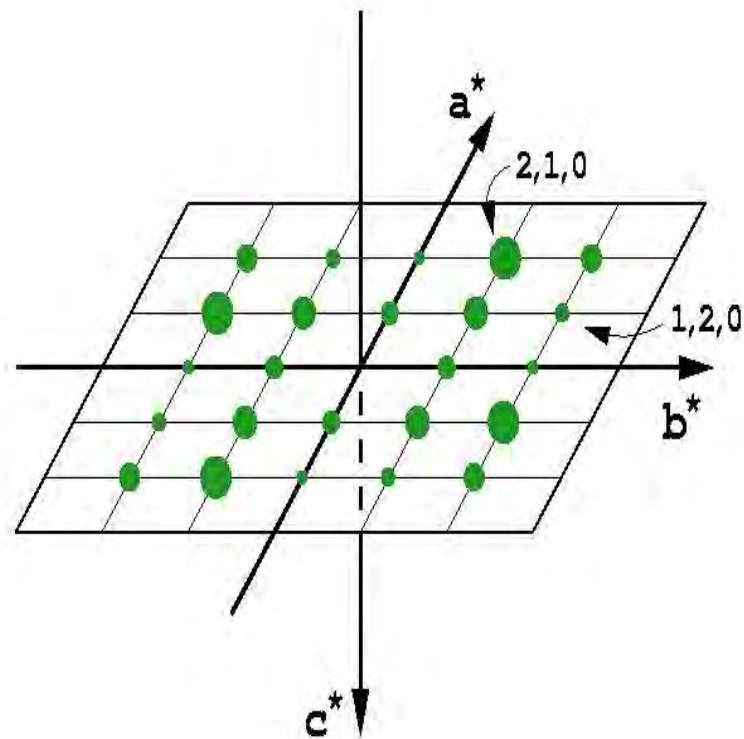
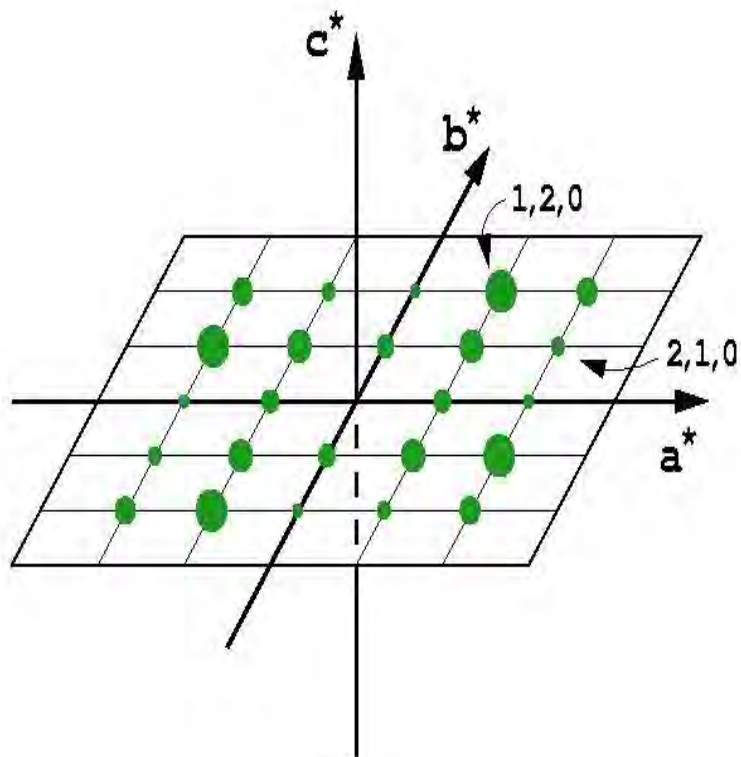








Alternative indexing



Alternative indexing

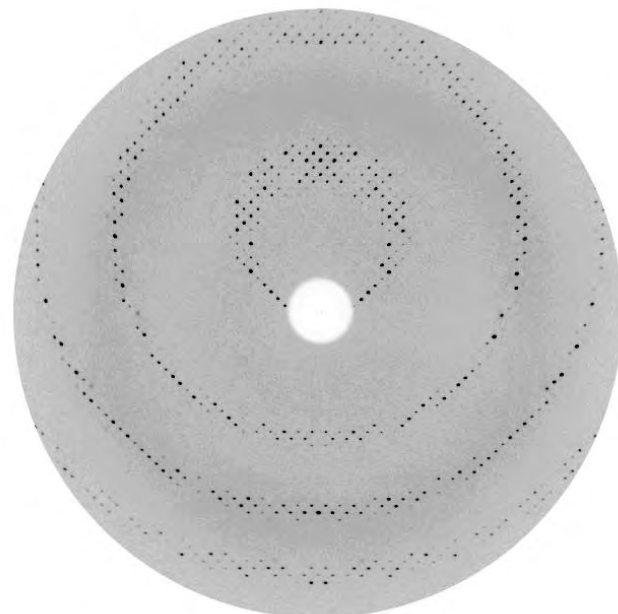
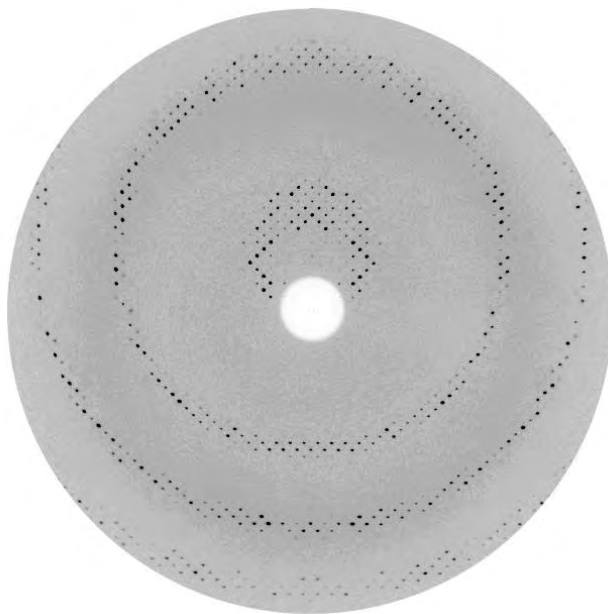
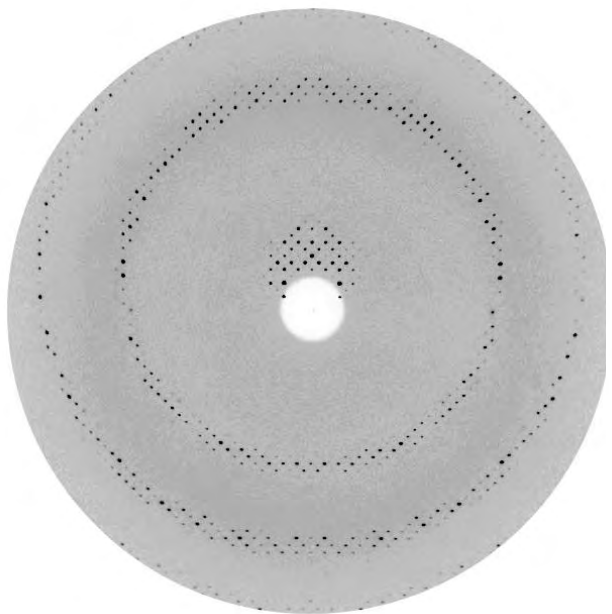
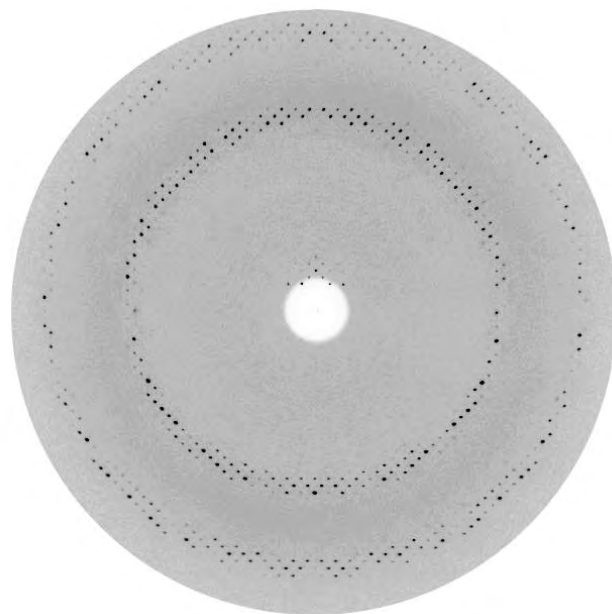
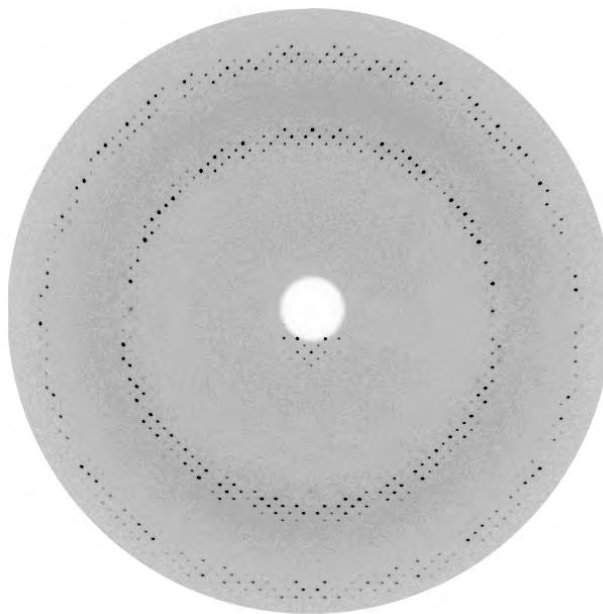
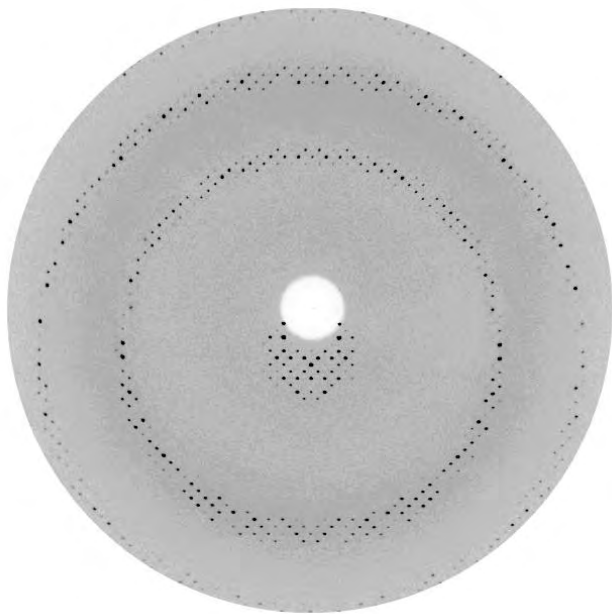
when lattice symmetry higher than space group
(with polar axes)

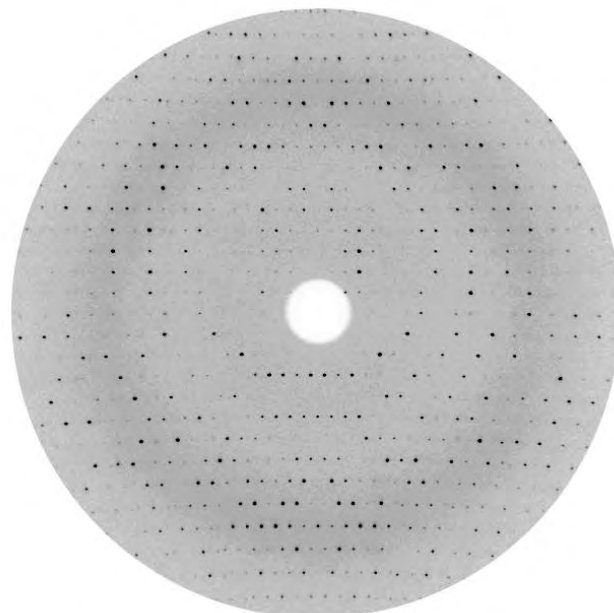
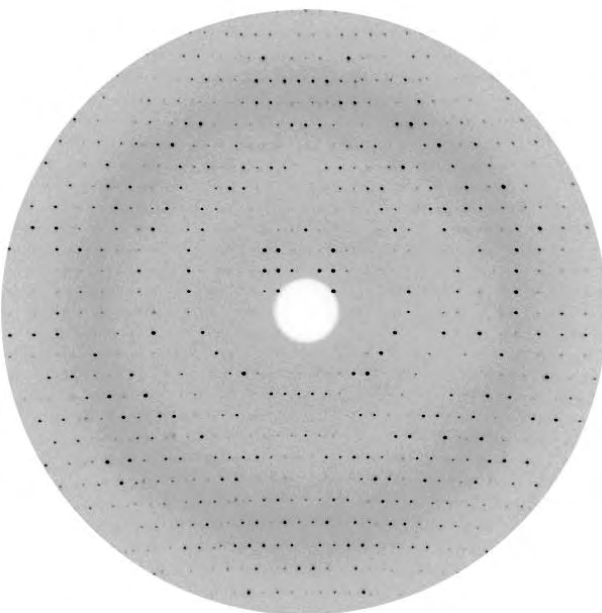
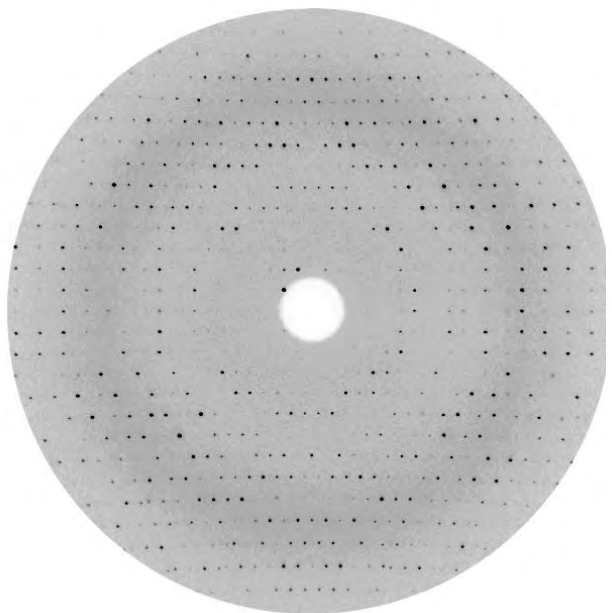
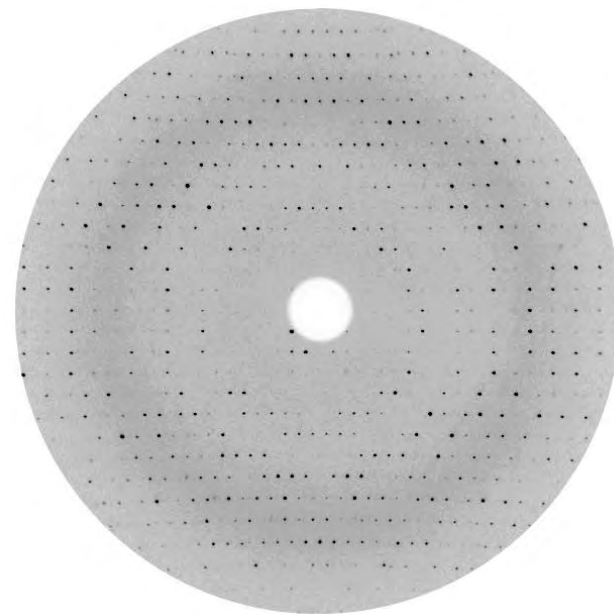
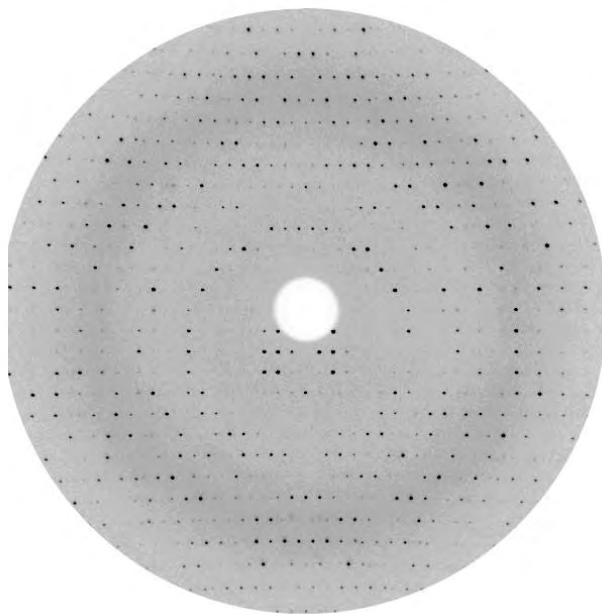
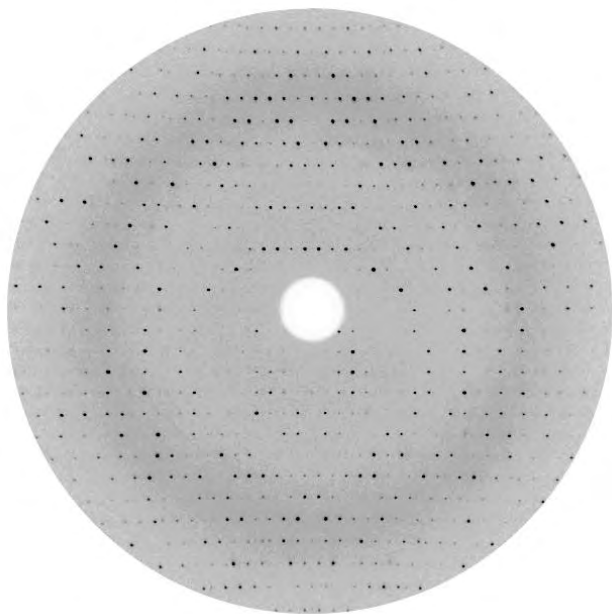
also merohedral twinning possible

- P4, I4
- P3, R3, P321, P312, P6
- P23, I23, F23

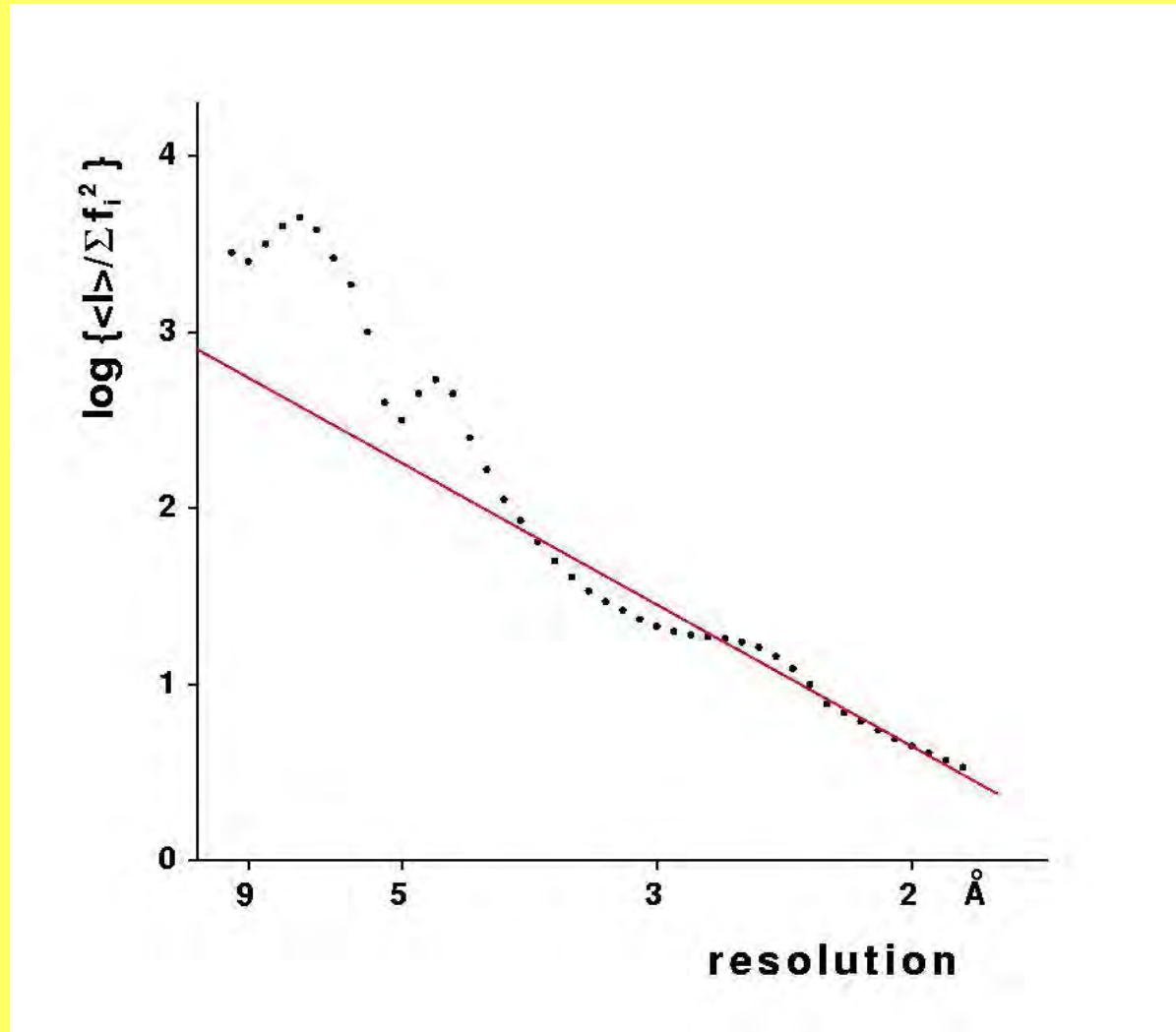
Or when some cell dimensions
coincidentally equal

Important with derivatives or data
from more than one crystal

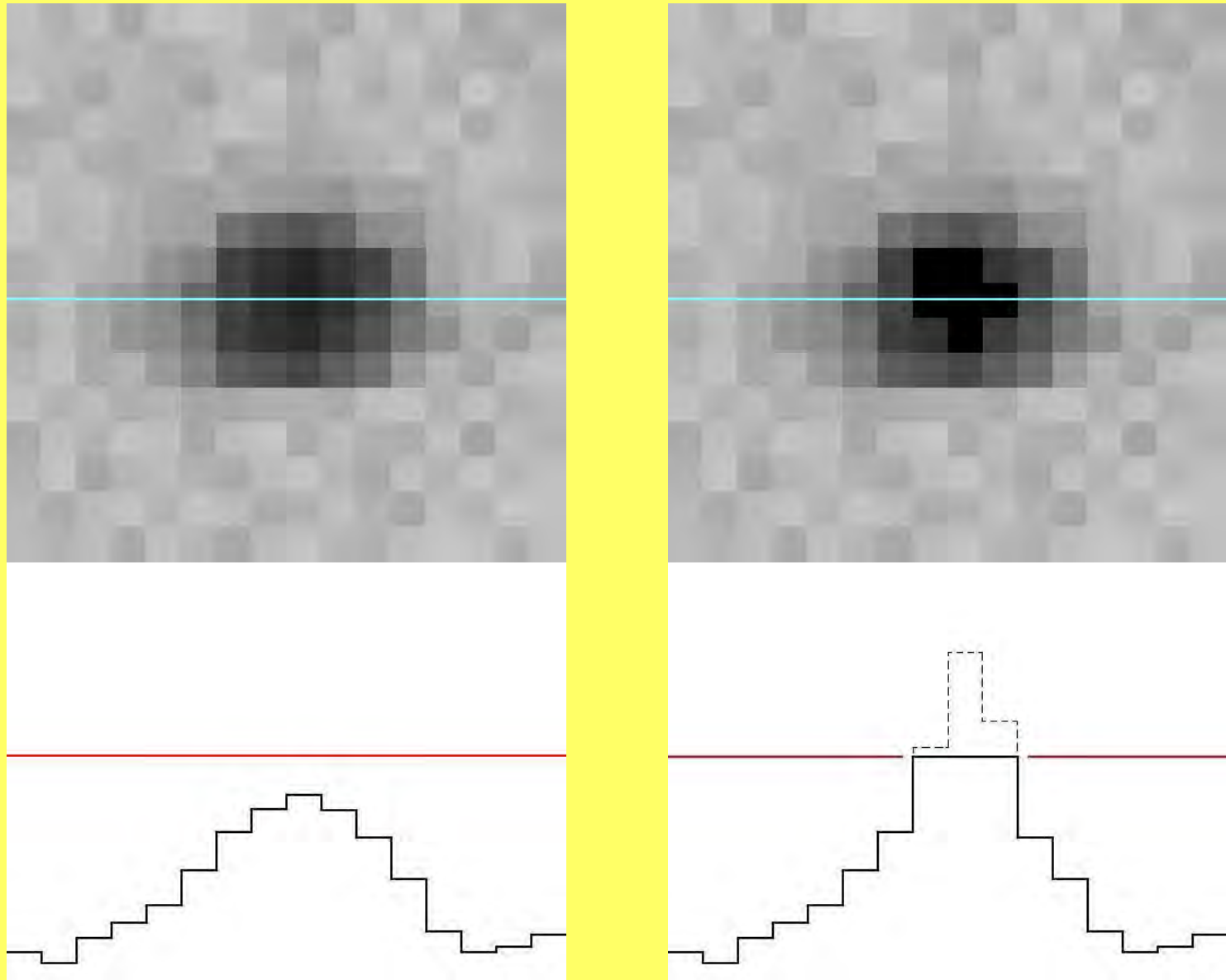




Wilson plot



Reflection profile with overloaded pixels



Strongest reflections are important

- for all methods based on Patterson and MR
- for direct methods
- they modulate Fourier maps
- not so crucial for refinement

Weak reflections

- bias results, if absent
- informative in pseudosymmetric cases

$$R_{\text{merge}} = \frac{\sum \{ \langle I \rangle - I_i \}}{\langle I \rangle}$$

$$R_{\text{meas}} = \frac{[n / (n-1)]^{1/2} * \sum \{ \langle I \rangle - I_i \}}{\langle I \rangle}$$

$I / \sigma(I)$ - better,
but σ 's must be
estimated correctly

2-D detectors do not provide
counting statistics -
- σ 's must be corrected

- by t-plot = $\frac{\langle I \rangle - I_i}{\sigma(I)}$

- or χ^2 criterion

important for programs
based on maximum likelihood

Data collection

- scientific process
not technicality
- irreversible consequences
(often)
- even more important due to
progress in automation,
phasing, refinement etc.

